



This project has received funding from the European Union's Horizon 2020 Research and Innovation programme under GA No 101004730.



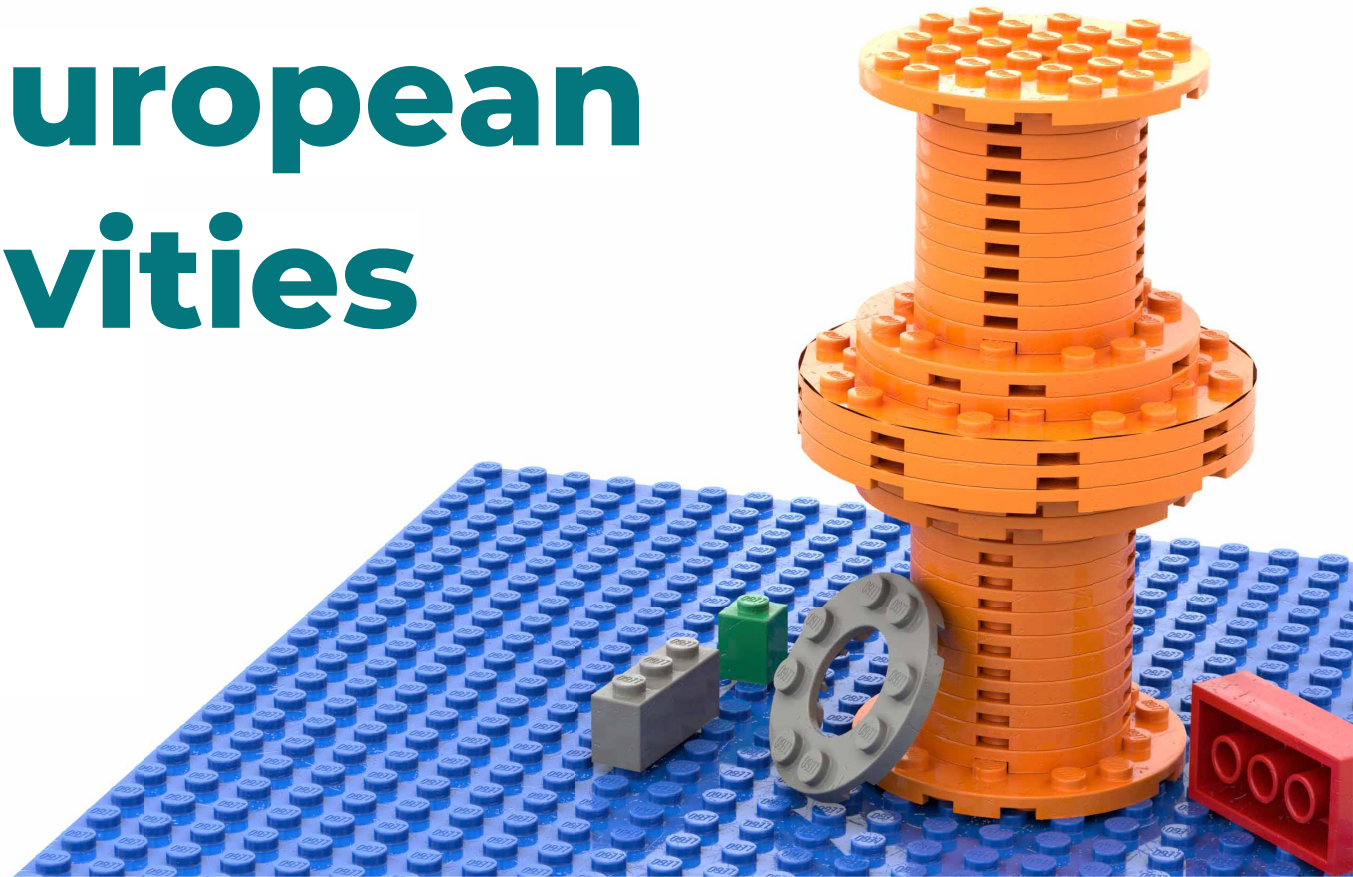
Cristian Pira

On Behalf of I.FAST WP9 Collaboration

# Progress in European Thin film activities



28 June 2023



# I.FAST WP9 Collaboration



C. Pira, O. Azzolini, R. Caforio, E. Chyhyrynets, D. Fonnesu, D. Ford, V. Garcia, G. Keppel, G. Marconato, A. Salmaso, F. Stivanello (LNL)  
 M. Bertucci, R. Paparella (LASA)  
 M. Bonesso, S. Candela, V. Candela, R. Dima, G. Favero, A. Pepato, P. Rebesan, M. Romanato (PD)



C.Z. Antoine, S. Berry, Y. Kalboussi, T. Proslie



D. Longuevergne, O. Hryhorenko,



E. Seiler, R. Ries



S. Keckert, O. Kugeler, J. Knobloch



S. Prucnal, S. Zhou



X. Jiang, T. Staedler, A. Zubitsovskii



R. Berton, D. Piccoli, F. Piccoli, G. Squizzato, F. Telatin



Medvids, A. Mychko, P. Onufrievs



O.B. Malyshev, R. Valizadeh, C. Benjamin, T. Sian, L. Smith,



G. Burt, N. Leicester, S. Marks, D. Seal, D. Turner



W. Bradley, S. Simon

## Associated Partners

 A. M. Valente Feliciano

## Informal Partners



*Energy saving is mandatory for the next generation accelerators...  
...cryogenics is one of the larger energy cost in modern SRF accelerators*

# I.FAST Goal (2025)

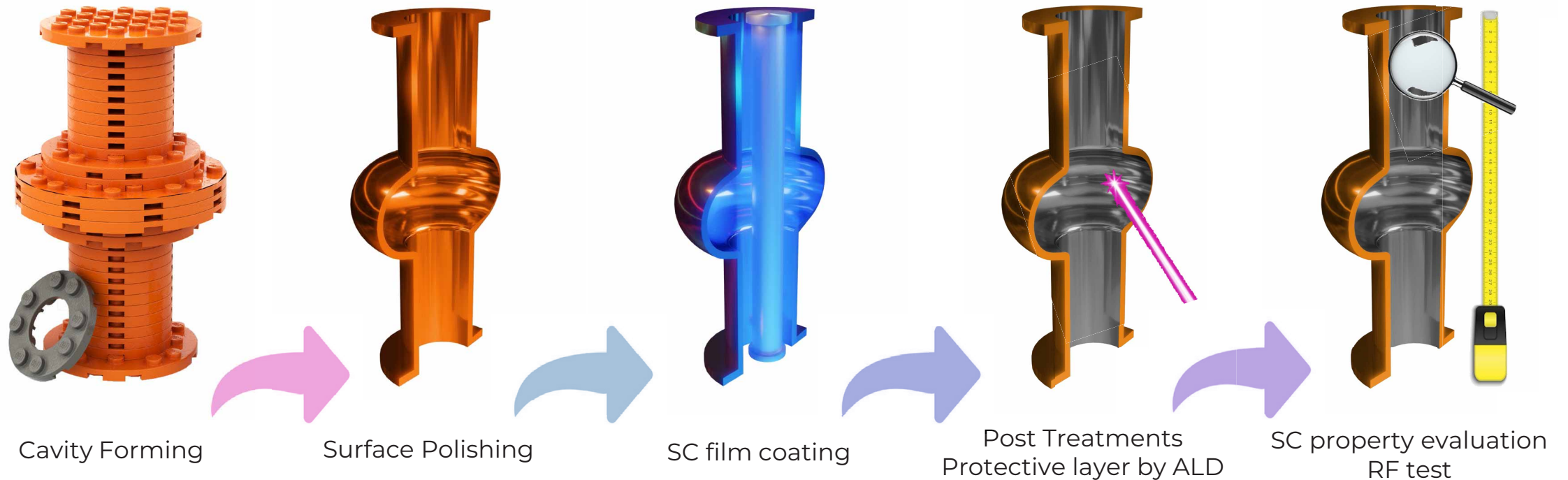
Realize a prototype of high performance  
1.3 GHz thin film SRF elliptical cavity  
 $Q > 1 \cdot 10^{10}$  @ 4.5 K

## Multiple challenges:

- ▶ Al5 are Brittle materials
- ▶ Complicate Phase Diagram
- ▶ Substrate preparation
- ▶ Low melting point substrate
- ▶ Interface diffusion
- ▶ Target Production
- ▶ Necessity of Test RF properties on simple geometry
- ▶ ...



# I.FAST R&D program cover all the production chain







# Cavity forming

# Seamless Spinning



Forming technology adopted to produce 1.3 GHz and 6 GHz elliptical seamless Cu R&D substrates to all partners



Cavity Forming



## PRIMARY GOAL:

High internal surface quality



## OPTIMIZED PRODUCTION PROTOCOL:

- ▶ CNC machine
- ▶ Reduced Annealing Temperature (400 °C, previous 500 °C)
- ▶ New intermediate Deep Drawing Step

# Additive Manufacturing



AM can open to a new way to design RF cavities

**GOAL:** Prove the possibility to polish properly the surface and get SRF state of the art performances

## COPPER

- ▶ Density 99.9%
- ▶ High quality surface after Vibrotumbling + EP
- ▶ Broken after long polishing (>500  $\mu\text{m}$  removed)
- ▶ Production of new optimized prototypes ongoing

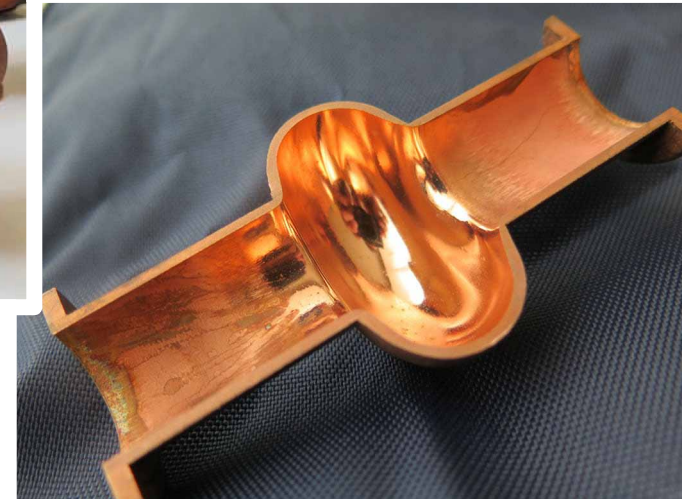


Despite the lower surface quality, Cu can be manufactured with low inclination angles



2 prototypes produced using TRUMPF TruPrint 5000

AM Cavity cutted after VB + EP of the cell



Cavity Forming



# Additive Manufacturing

AM can open to a new way to design RF cavities

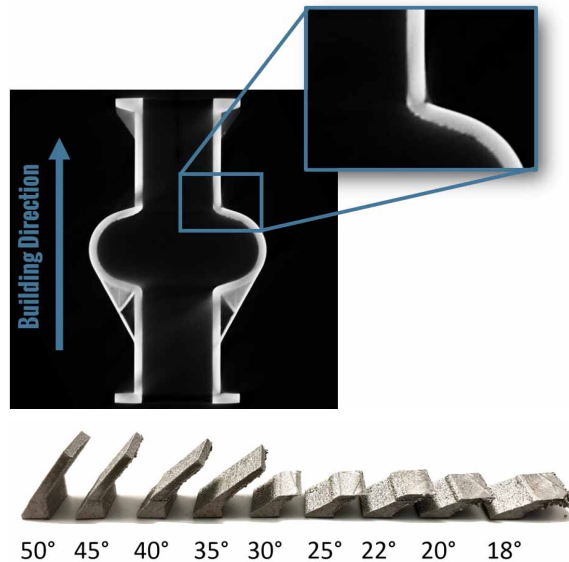
**GOAL:** Prove the possibility to polish properly the surface and get SRF state of the art performances



Cavity Forming

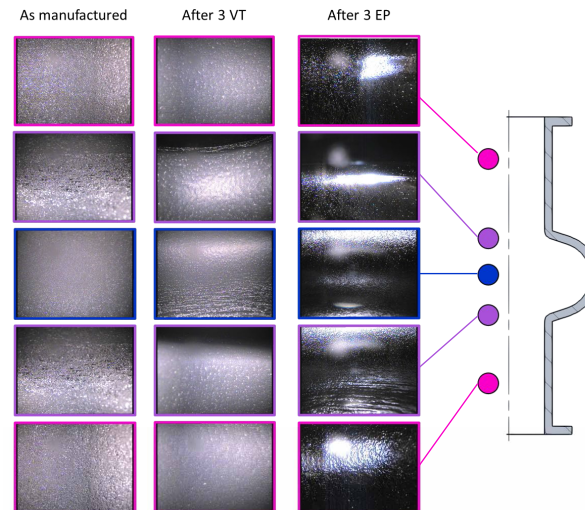


## NIOBIUM



Down skin optimization

Critical Angle = 35°



Vibrotumbling + EP

Ra = 40 um → 0.4 um

- ▶ Tc=9.2 K
- ▶ RRR = 10
- ▶ No leak at room T
- ▶ Ready for cryogenic and RF test



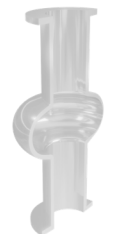
# Additive Manufacturing



AM can open to a new way to design RF cavities



Cavity Forming



**Davide Ford**

**Poster today:** WEPWB119

Additive Manufacturing of Pure Niobium and Copper  
Using Laser Powder Bed Fusion for Particle Accelerator Applications

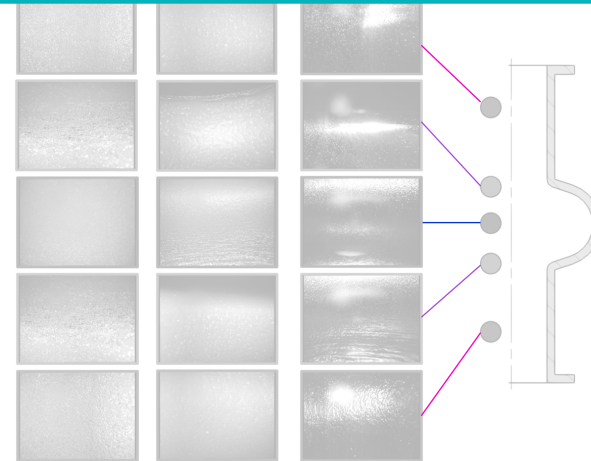
NIOBIUM



50° 45° 40° 35° 30° 25° 22° 20° 18°

Down skin optimization

Critical Angle = 35°



**Vibrotumbling + EP**

Ra = 40 um → 0.4 um

RRR = 10

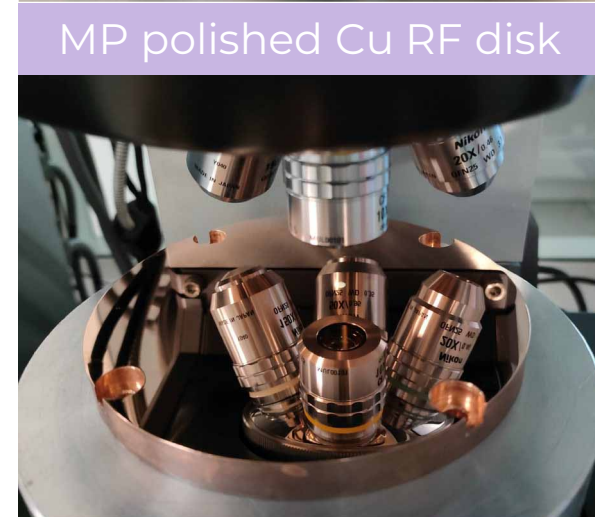
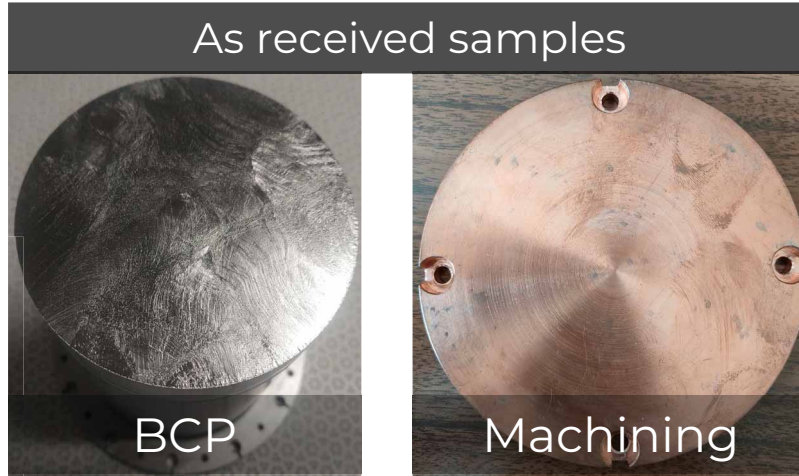
No leak at room T

Ready for cryogenic  
and RF test



# Surface polishing

# Metallographic Polishing



Surface Polishing



Courtesy of Oleksandr Hryhorenko, Claire Antoine and David Longuevergne

# Metallographic Polishing



As received samples



**Oleksandr Hryhorenko**

**Talk today at 12:20: WEIXA06**

Recent advances on metallographic polishing for SRF application



**Oleksandr Hryhorenko**

**Poster today: WEPWB050**

Exploring innovative pathway of cavity fabrication for SRF application



Surface Polishing

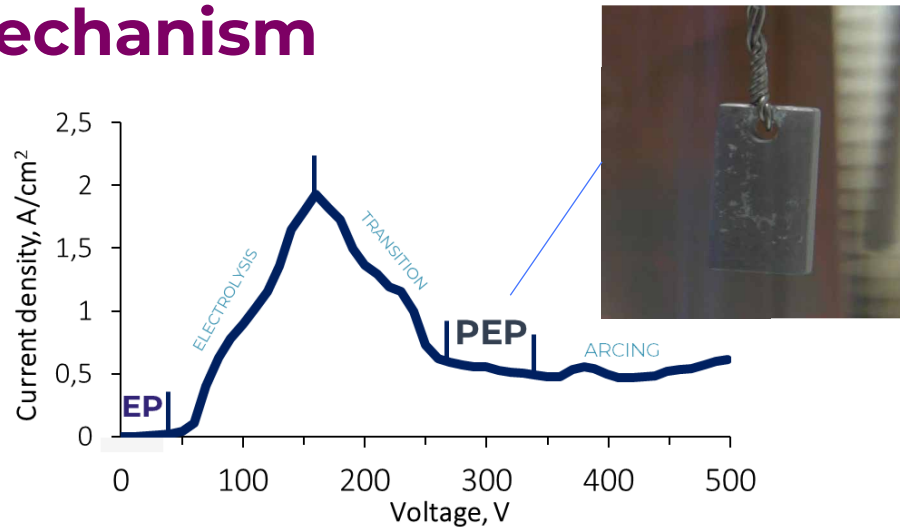


Courtesy of Oleksandr Hryhorenko, Claire Antoine and David Longuevergne



# Plasma Electrolytic Polishing PEP

## Mechanism



## Advantages



**“Green”** water-based salt solutions! No HF acid!  
 Nb -  $NH_4F$  &  $NaF$ , Cu -  $SUBU5$  or  $(NH_4)_2HPO_4$  or  $K_2P_2O_7$



**5-30 times faster** than regular EP  
 Up to  $30 \mu m/min$ , significant reduction polishing time  
 From a full day to a couple of hours to treat a cavity!

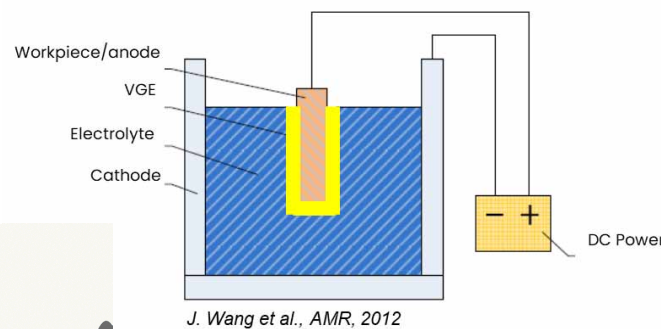
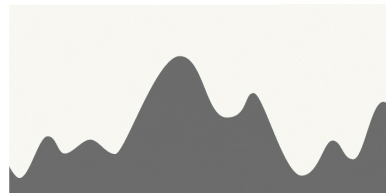


**Lowest roughness** 5-50 nm achievable  
 Efficient polishing! Equal thickness removal yield lowest roughness among traditional polishing (EP, BCP, SUBU)



**No preparation** of surface is required  
 PEP can substitute mechanical polishing steps (CBP, grinding, tumbling)

Same EP set-up  
 Different regime



J. Wang et al., AMR, 2012



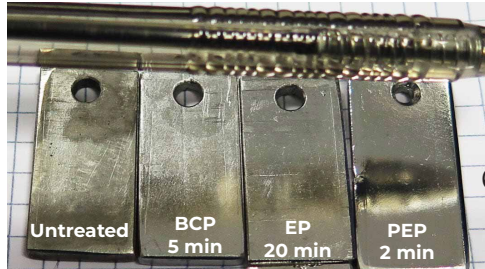
Surface Polishing



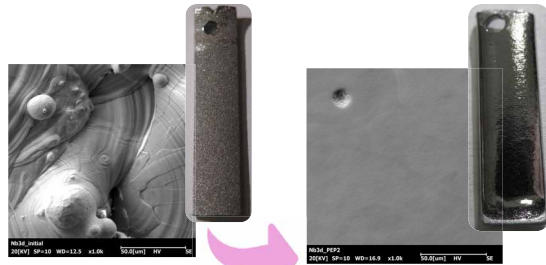
# Plasma Electrolytic Polishing PEP Results

1x Nb 3x Cu  
Solution Patentees by INFN

Nb planar samples



6.5 μm removed



Initial Ra= 13 μm  
PEP 30 min Ra= 1.5 μm

Additive Manufacturing



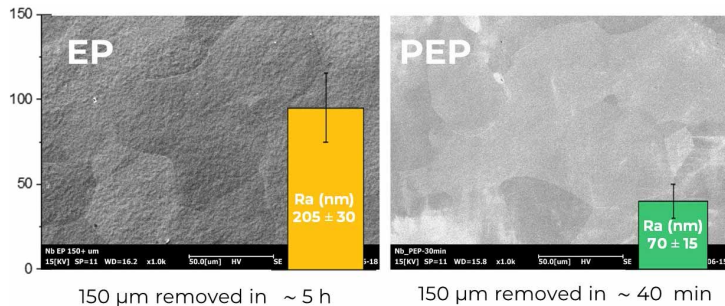
Nb QPR polishing optimization on-going

Full Cu QPR ready for coating

QPR Samples

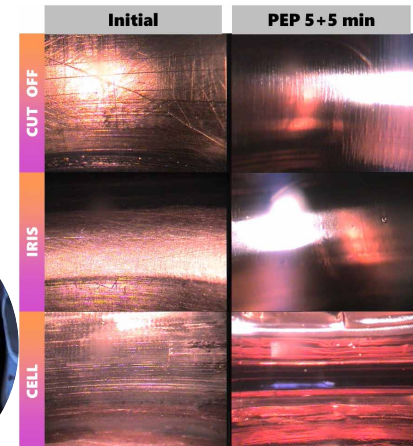


Surface Polishing



6 GHz Cu cavity  
No internal cathode was used!

70 μm removed in 10 minutes  
30 A (100 cm<sup>2</sup> → 1.3 GHz ~ 300 A)

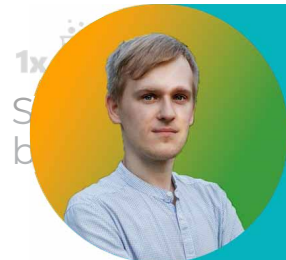


# Plasma Electrolytic Polishing PEP Results

Nb QPR polishing optimization on-going



Surface Polishing



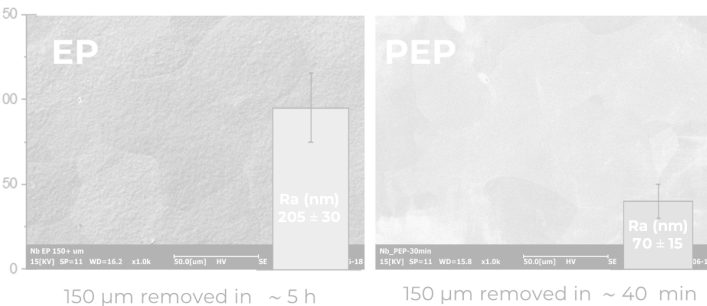
**Eduard Chyhyrynets**  
**Poster on Moday: MOPMB009**

Plasma Electrolytic Polishing  
Technology Progress Development for Nb and Cu Substrate Preparation



6.5  $\mu\text{m}$  removed  
Ra = 13  $\mu\text{m}$   
Ra = 1.5  $\mu\text{m}$   
1000 X  
Additive Manufacturing

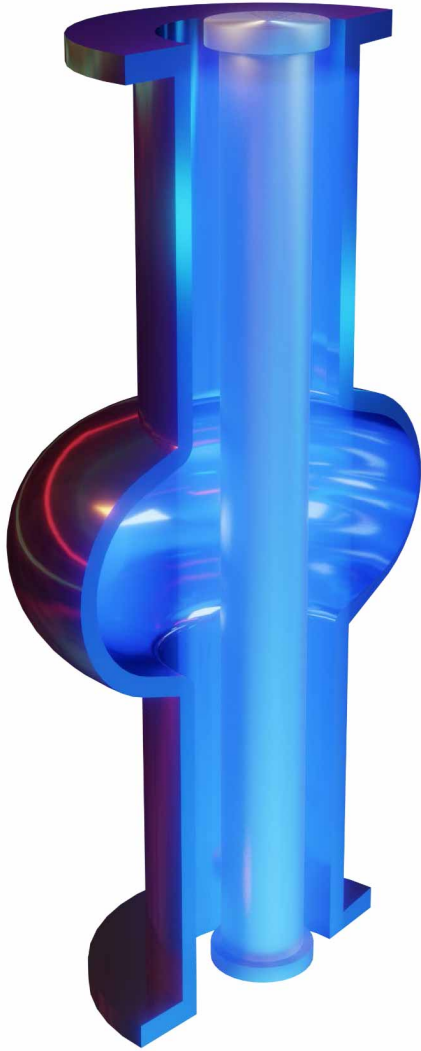
Nb planar samples



6 GHz Cu cavity

No internal cathode was used  
70  $\mu\text{m}$  removed in 10 minutes  
30 A (100  $\text{cm}^2 \rightarrow 1.3 \text{ GHz} \sim 300 \text{ A}$ )





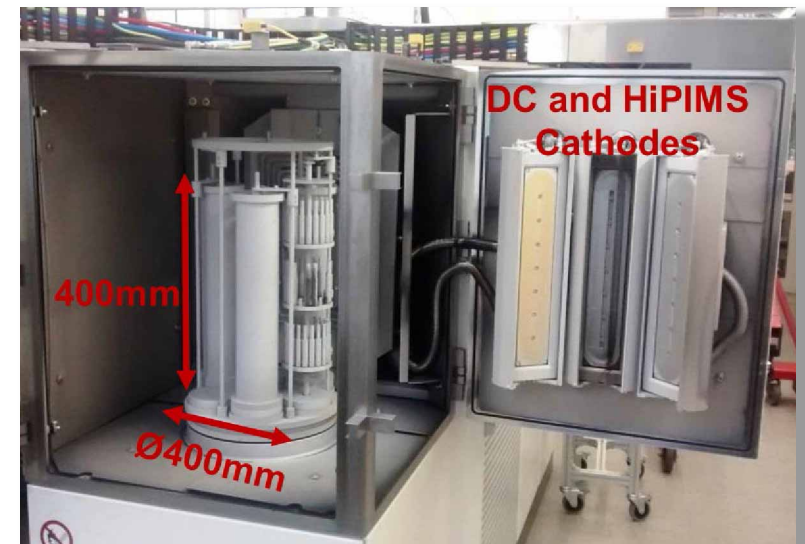
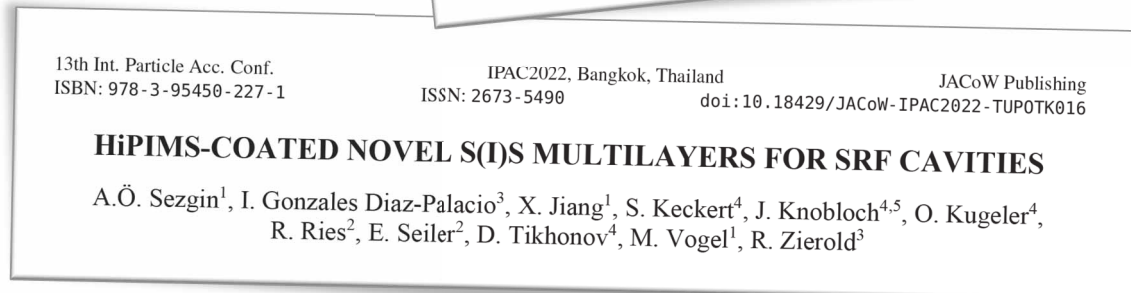
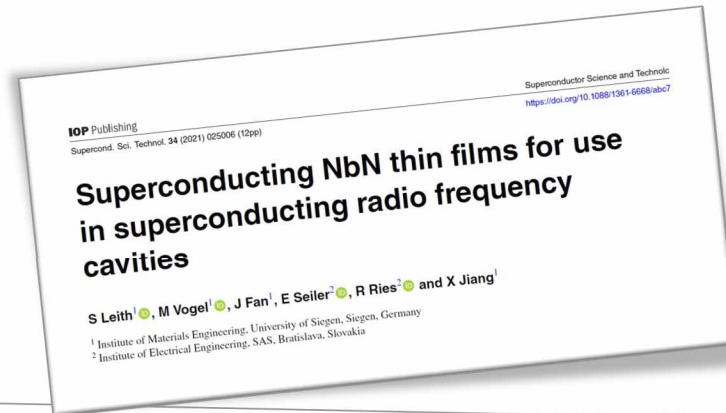
# SC Coatings



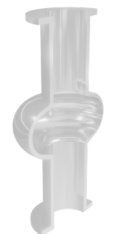
# NbTiN SC coatings

From **NbN** to **NbTiN** by HiPIMS

Goal: **SIS structure** by PVD+ALD



SC coatings

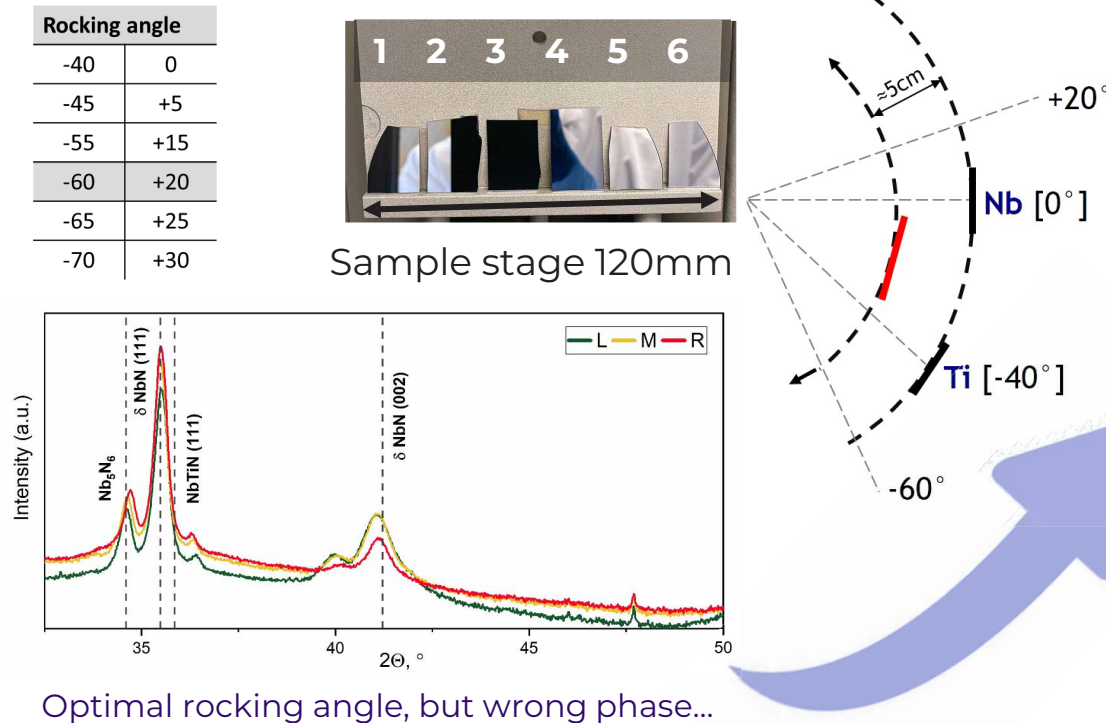


Courtesy of A. Zubtsovskii

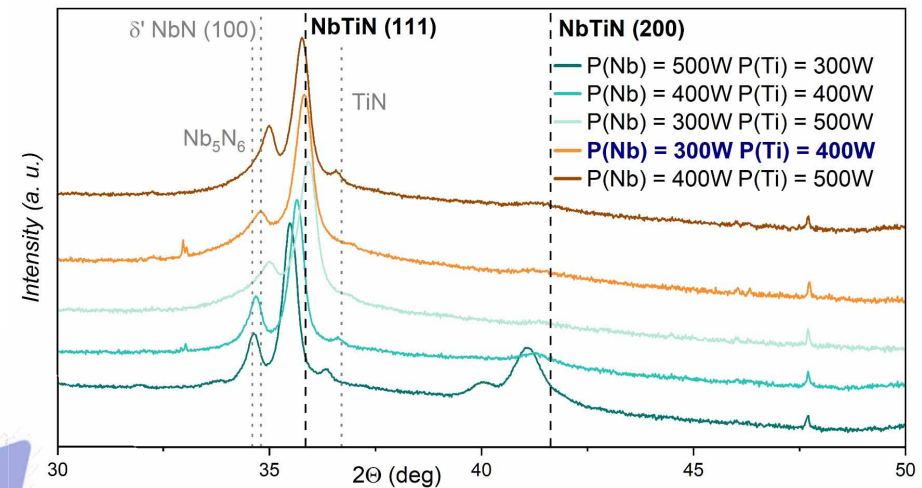
# NbTiN SC coatings

## PARAMETER OPTIMIZATION

Defined the **optimal rocking angle** in Nb-Ti co-sputtering



Defined the **optimal Cathode Power**:  
 $P(\text{Nb}) = 300\text{W}$     $P(\text{Ti}) = 400\text{W}$



**Right NbTiN phase obtained**

Other parameters (P, Ar/N<sub>2</sub> ratio, bias V, ...) must be explored to reduce spurious phases



SC coatings

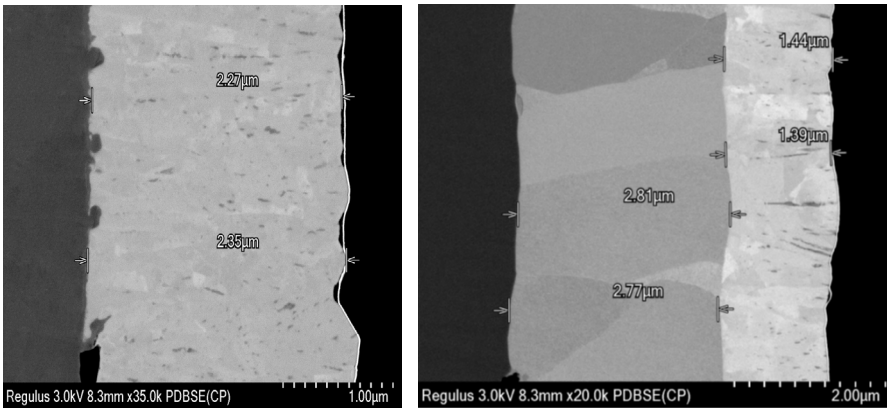


Courtesy of A. Zubitsovskii

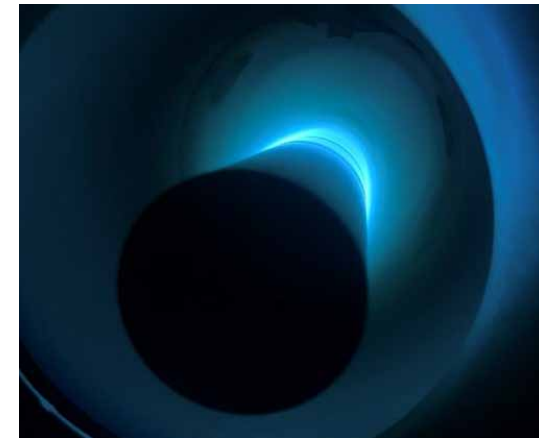
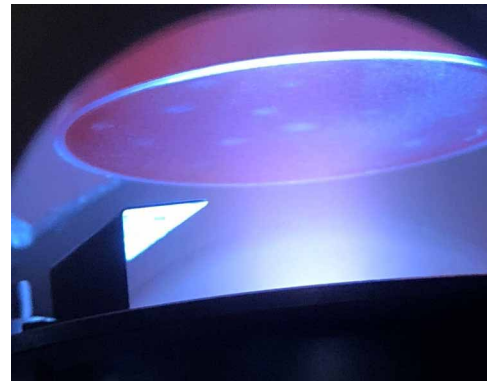
# Nb<sub>3</sub>Sn, V<sub>3</sub>Si, NbTiN SC coatings



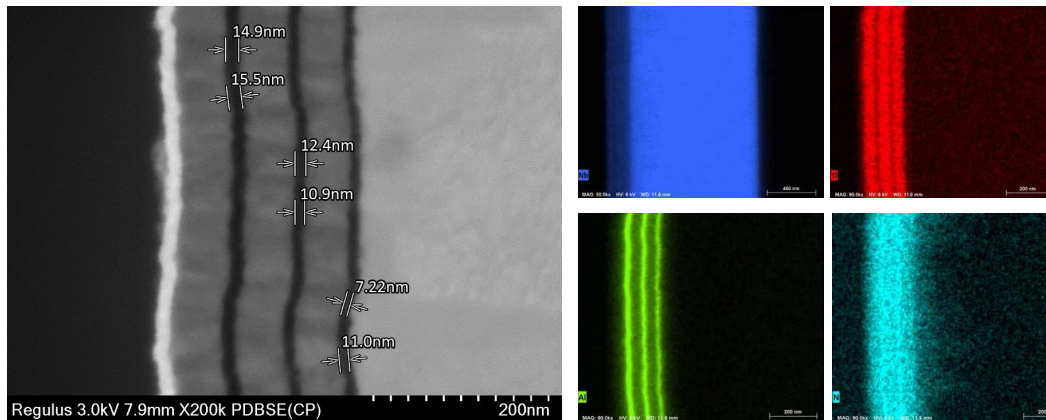
Science and  
Technology  
Facilities Council



Nb<sub>3</sub>Sn on Cu and Nb<sub>3</sub>Sn on Cu with Nb barrier layer



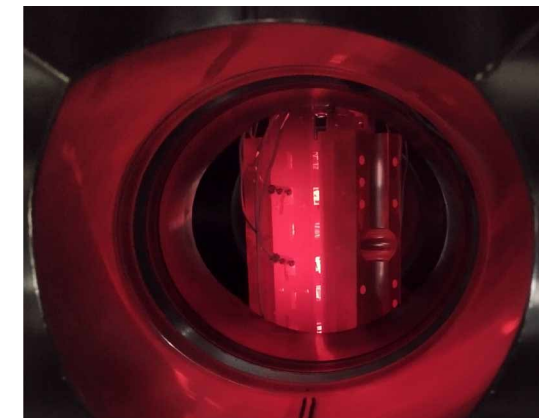
Development of 6 GHz and  
1.3 GHz cavity coating system



SIS multilayer structure (Nb/AlN/Nb<sub>3</sub>Sn) deposited on Ta



A QPR sample during and  
after the Nb deposition



Coating of 6 GHz split cavity



SC coatings



Courtesy of R. Valizadeh



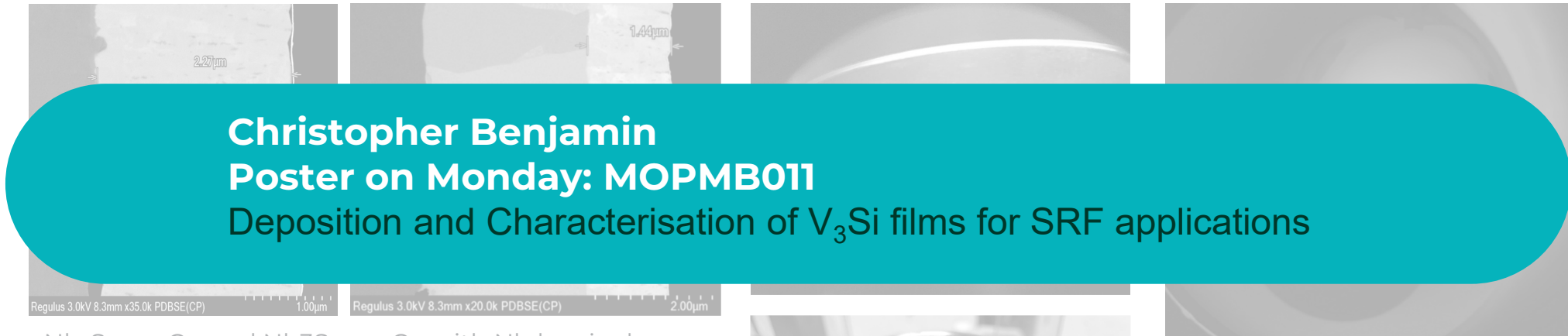
# Nb<sub>3</sub>Sn, V<sub>3</sub>Si, NbTiN SC coatings



Science and  
Technology  
Facilities Council



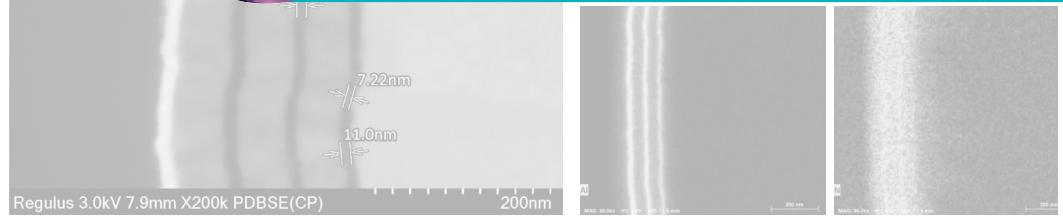
SC coatings



**Christopher Benjamin**  
**Poster on Monday: MOPMB011**  
Deposition and Characterisation of V<sub>3</sub>Si films for SRF applications



**Daniel .J. Seal**  
**Poster on Monday: MOPMB062**  
Optimisation Of Niobium Thin Film Deposition Parameters For SRF Cavities



SIS multilayer structure (Nb/AlN/Nb<sub>3</sub>Sn) deposited on Ta



A QPR sample during and after the Nb deposition

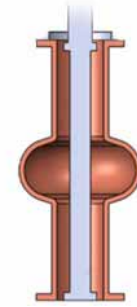


Coating of 6 GHz split cavity





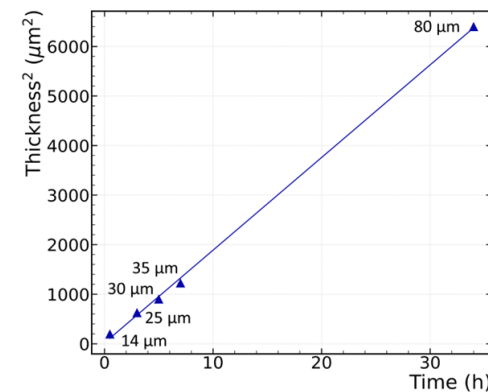
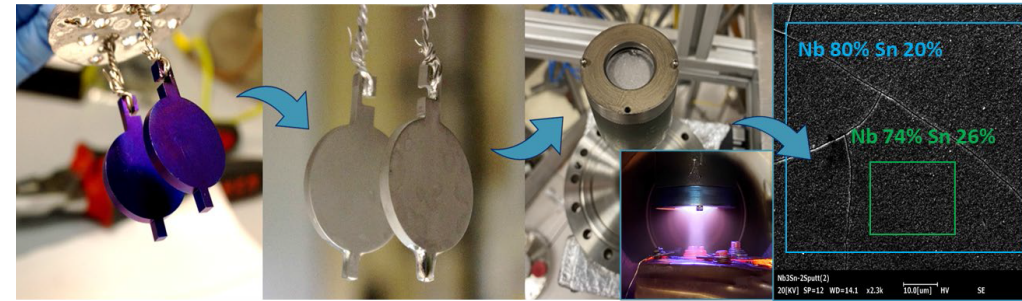
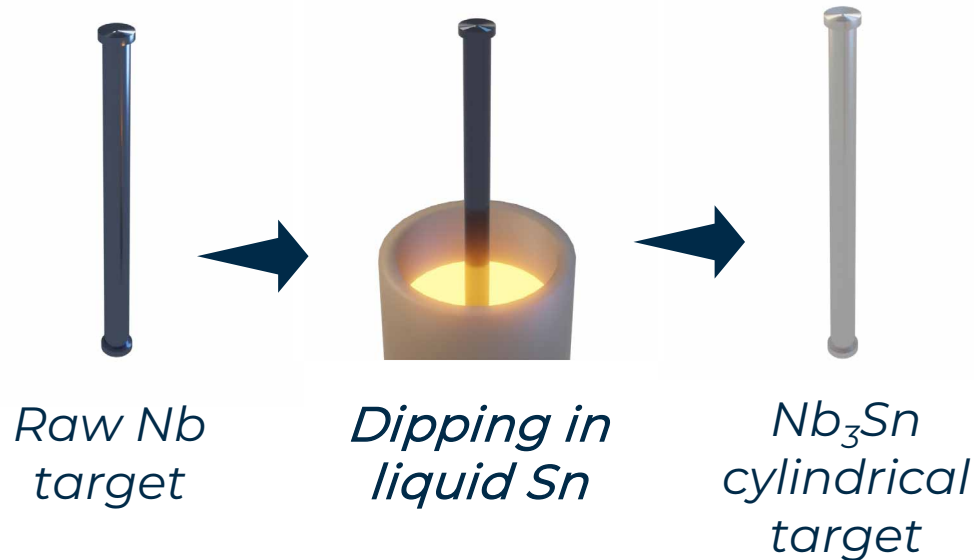
# Nb<sub>3</sub>Sn coatings



Single target configuration **easiest to scale** onto elliptical geometry

Nb<sub>3</sub>Sn cylindrical target are not commercially available

## LNL Strategy for Nb<sub>3</sub>Sn cylindrical target production



Nb<sub>3</sub>Sn **thickness** related to **dipping time**

Possible **tin content modulation**



# Nb<sub>3</sub>Sn coatings



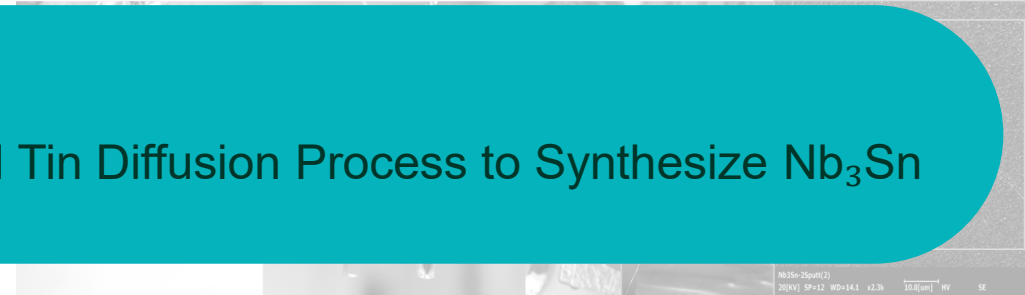
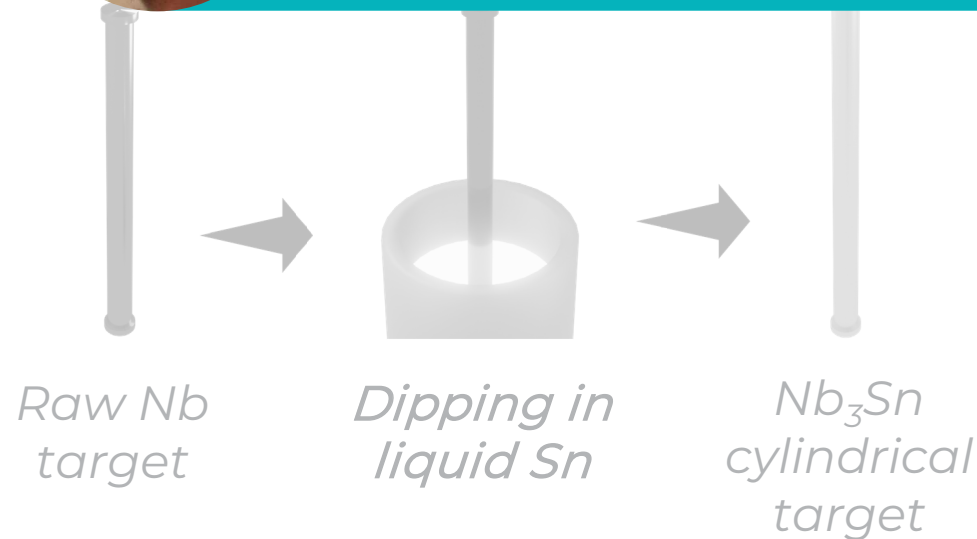
Nb<sub>3</sub>Sn cylindrical target are not commercially available



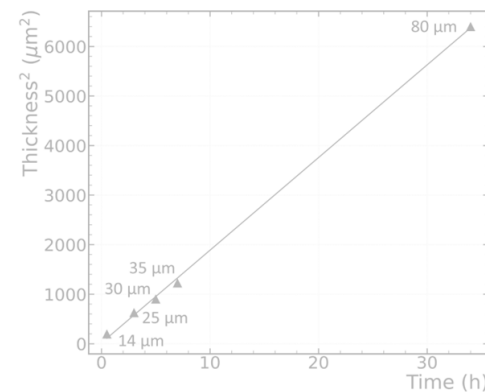
**Davide Ford**

**Poster today:** WEPWB118

Study and Improvements of Liquid Tin Diffusion Process to Synthesize Nb<sub>3</sub>Sn Cylindrical Targets



Proof of concept



Nb<sub>3</sub>Sn **thickness** related to **dipping time**

Possible **tin content modulation**



SC coatings



# Nb<sub>3</sub>Sn coatings

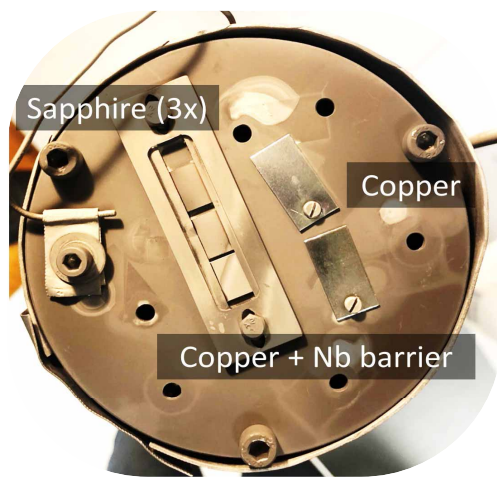


## Sputtering parameter optimization

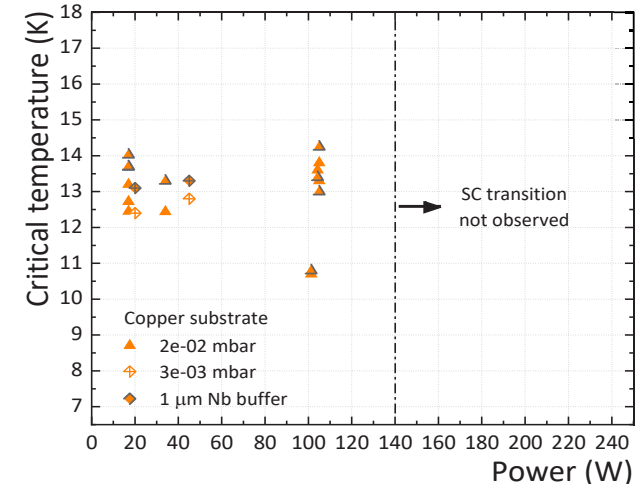
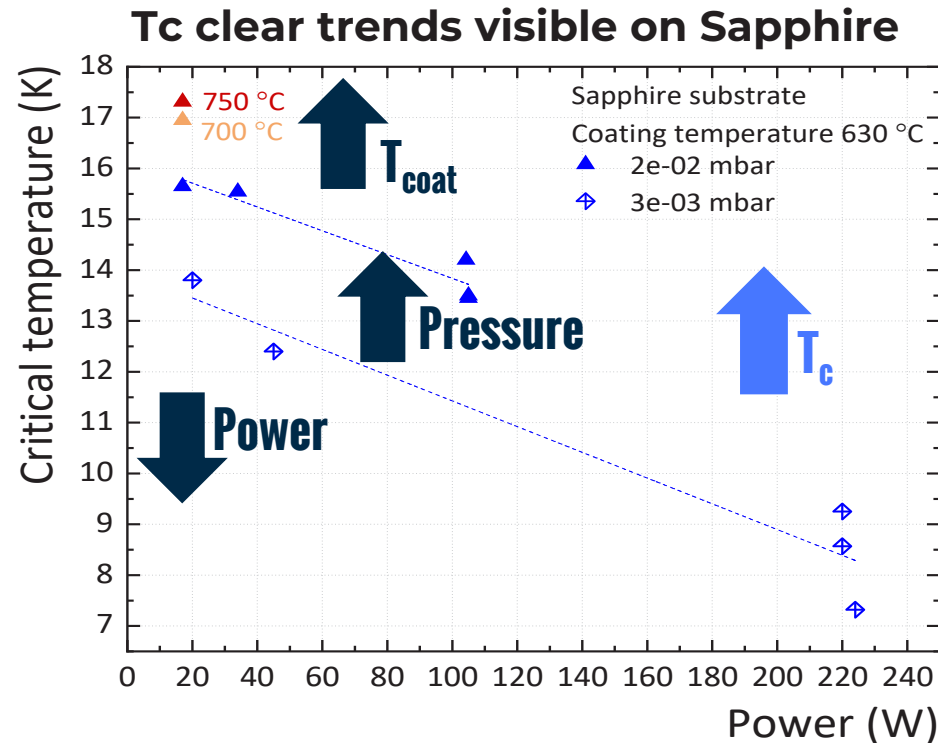
Nb<sub>3</sub>Sn deposited via DCMS from 4" planar stoichiometric target in Ar atmosphere



Single target configuration **easiest to scale** onto elliptical geometry



In the same run different substrates are coated in the same conditions



Nb<sub>3</sub>Sn T<sub>c</sub> sticks at 14 K on Cu

**Interface effect**



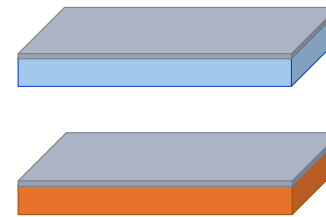
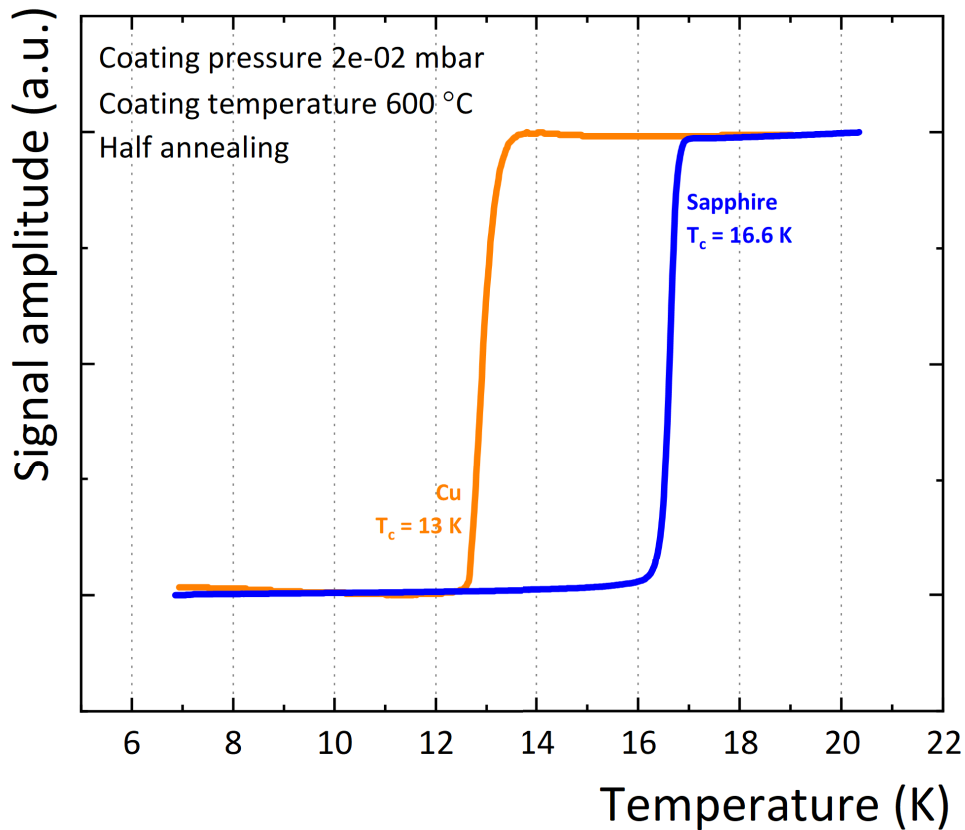
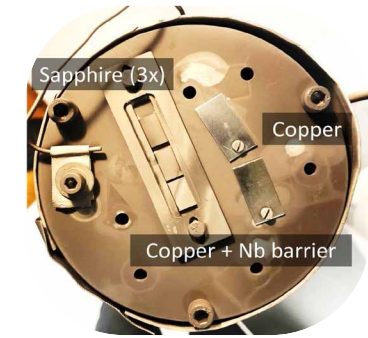
SC coatings



# Nb<sub>3</sub>Sn coatings



## Sputtering parameter optimization



Sapphire + 1 μ Nb<sub>3</sub>Sn

Cu + 1 μ Nb<sub>3</sub>Sn



SC coatings

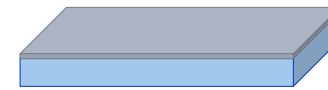
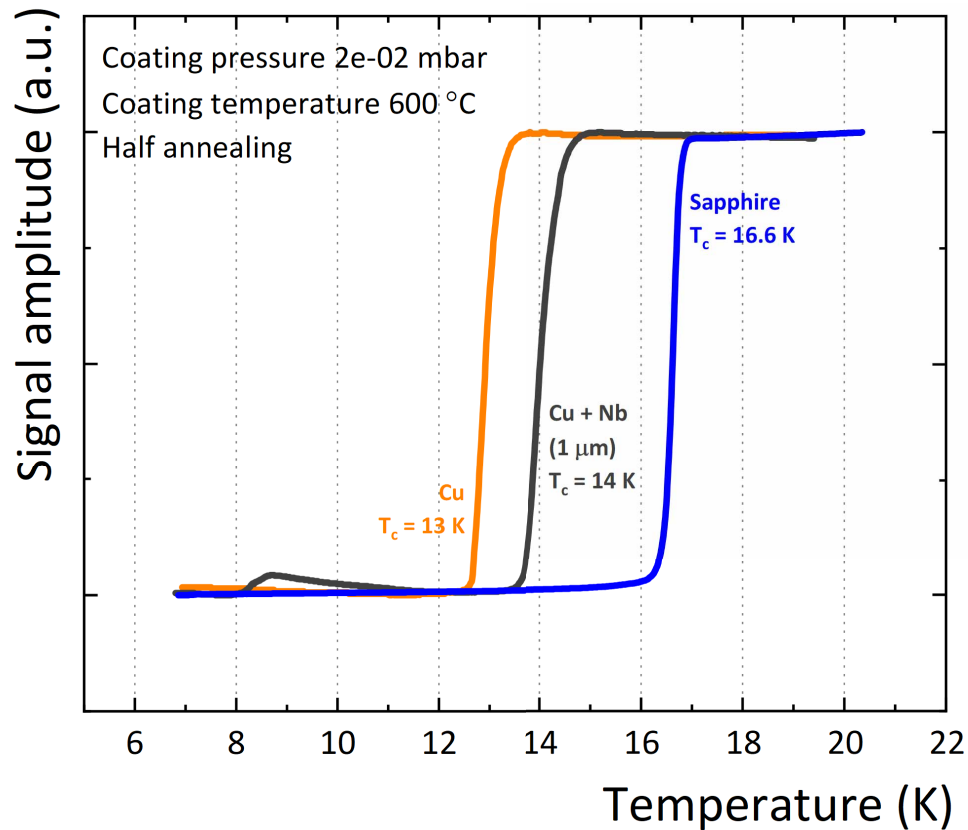
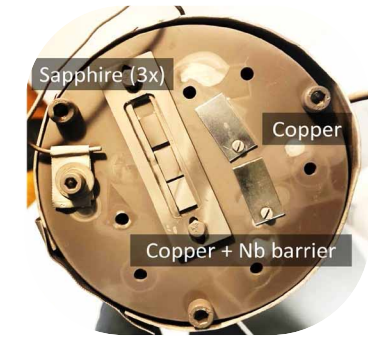




# Nb<sub>3</sub>Sn coatings



## Sputtering parameter optimization



Sapphire + 1 μ Nb<sub>3</sub>Sn



Cu + 1 μ Nb<sub>3</sub>Sn



Cu + 1 μ Nb + 1 μ Nb<sub>3</sub>Sn



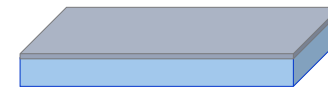
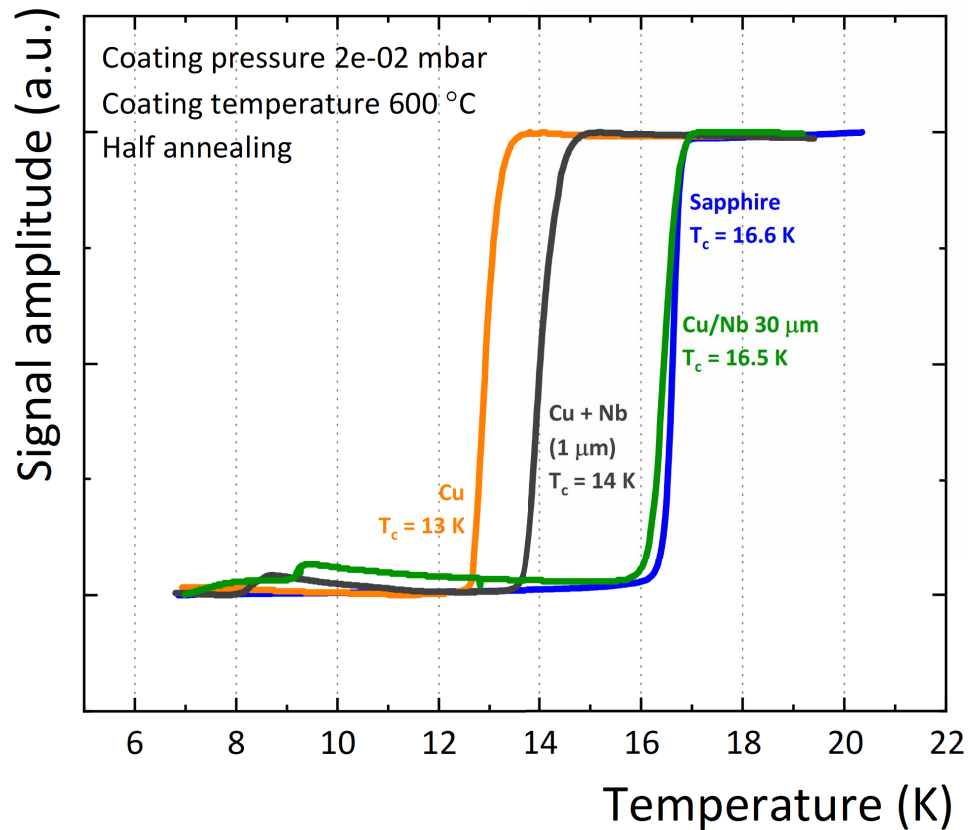
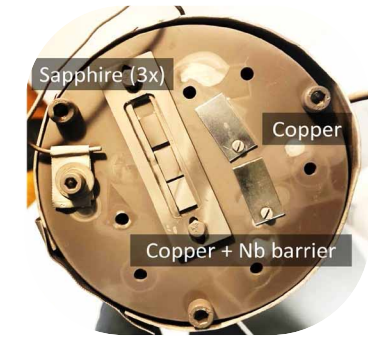
SC coatings



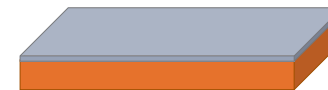
# Nb<sub>3</sub>Sn coatings



## Sputtering parameter optimization



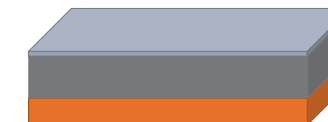
Sapphire + 1  $\mu$ m Nb<sub>3</sub>Sn



Cu + 1  $\mu$ m Nb<sub>3</sub>Sn



Cu + 1  $\mu$ m Nb + 1  $\mu$ m Nb<sub>3</sub>Sn

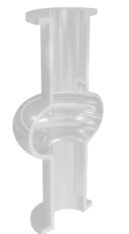


Cu + 30  $\mu$ m Nb + 1  $\mu$ m Nb<sub>3</sub>Sn

**A very thick Nb barrier layer can prevent diffusion at the interface**



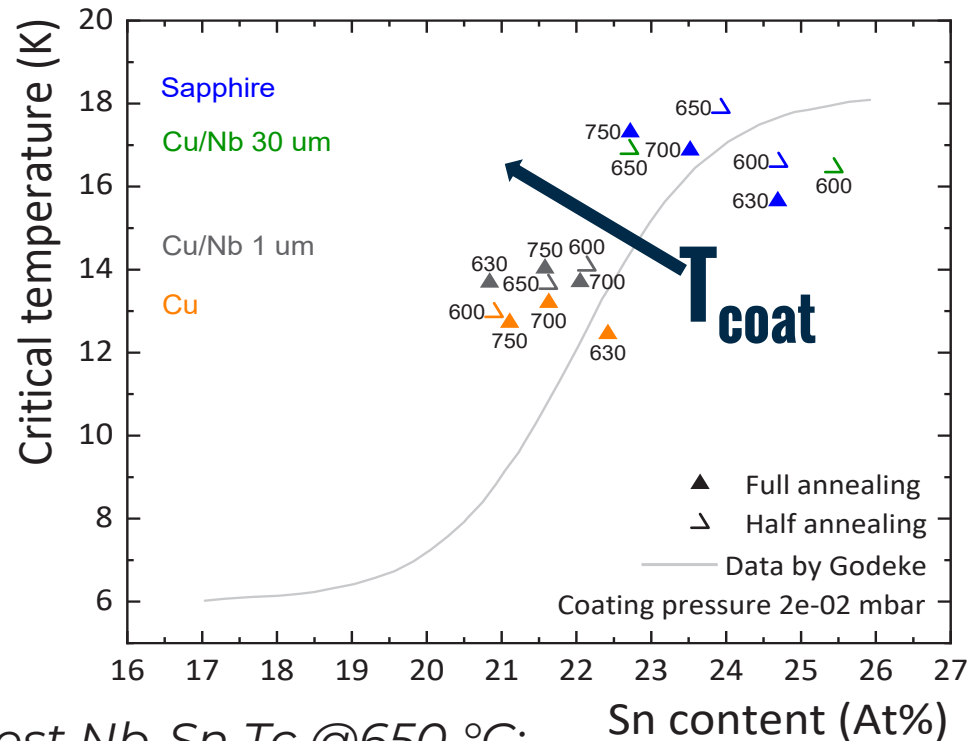
SC coatings



# Nb<sub>3</sub>Sn coatings



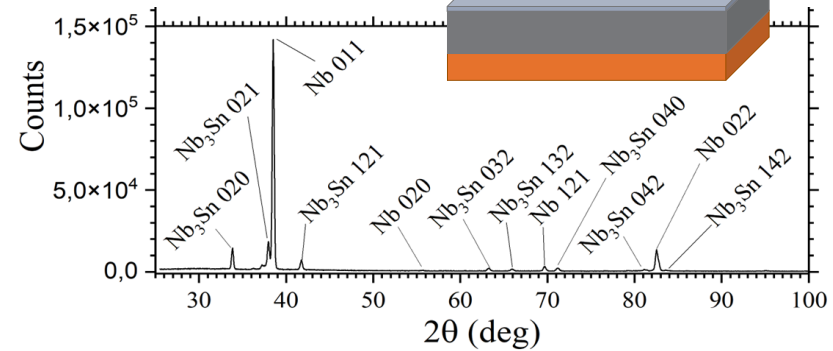
## Sputtering parameter optimization



Best Nb<sub>3</sub>Sn T<sub>c</sub> @650 °C:

- ▶ 18 K on Sapphire
- ▶ 17 K on Cu + barrier

Cu + 30 μ Nb + 1 μ Nb<sub>3</sub>Sn



**Only Nb<sub>3</sub>Sn phase present**

**Ready to coat a QPR for RF test**

Room for further improvements:

- ▶ Barrier layer thickness, other materials, ...
- ▶ Annealing time, Temperature, SC film thickness, ...

▶ **Alternative ways to prevent diffusion**



SC coatings

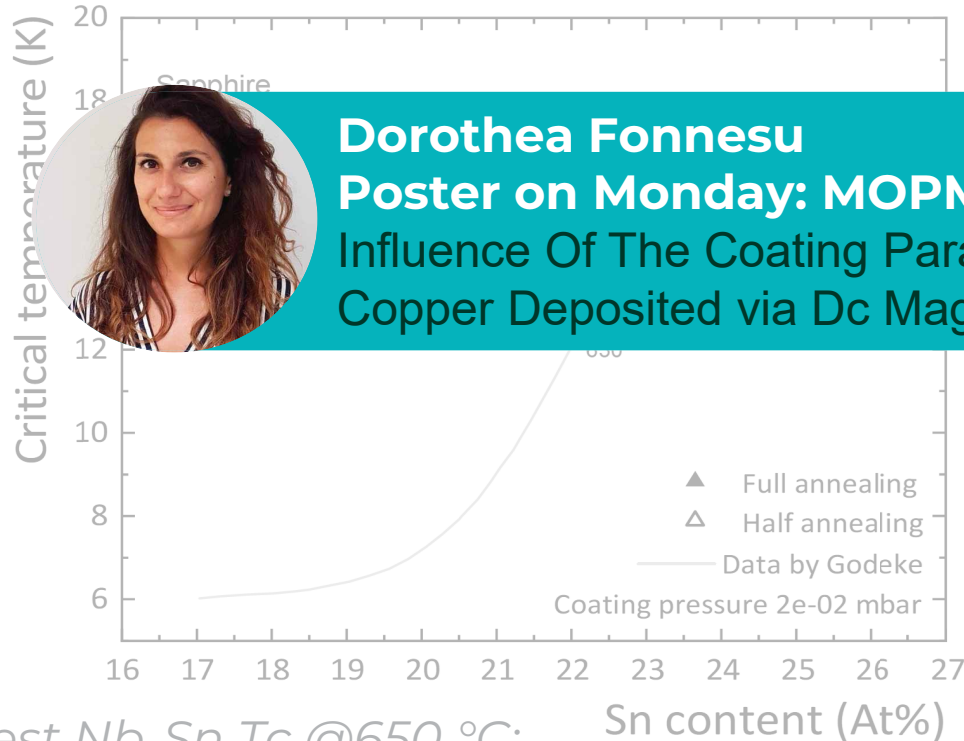


# Nb<sub>3</sub>Sn coatings



## Sputtering parameter optimization

Cu + 30 μ Nb + 1 μ Nb<sub>3</sub>Sn



**Dorothea Fonnesu**

**Poster on Monday: MOPMB013**

Influence Of The Coating Parameters on the T<sub>c</sub> of Nb<sub>3</sub>Sn Thin Films on Copper Deposited via Dc Magnetron Sputtering

Only Nb<sub>3</sub>Sn phase present

Ready to coat a QPR for RF test

Room for further improvements:

- ▶ Barrier layer thickness, other materials, ...
- ▶ Annealing time, Temperature, SC film thickness, ...

Best Nb<sub>3</sub>Sn T<sub>c</sub> @650 °C:

- ▶ 18 K on Sapphire
- ▶ 17 K on Cu + barrier

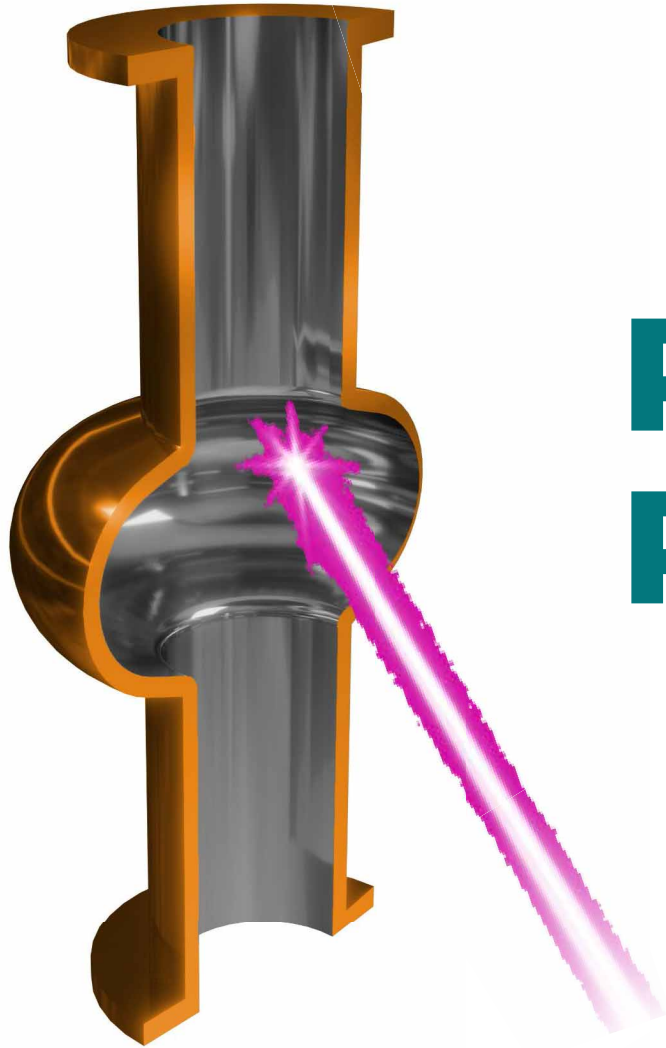
▶ **Alternative ways to prevent diffusion**



SC coatings





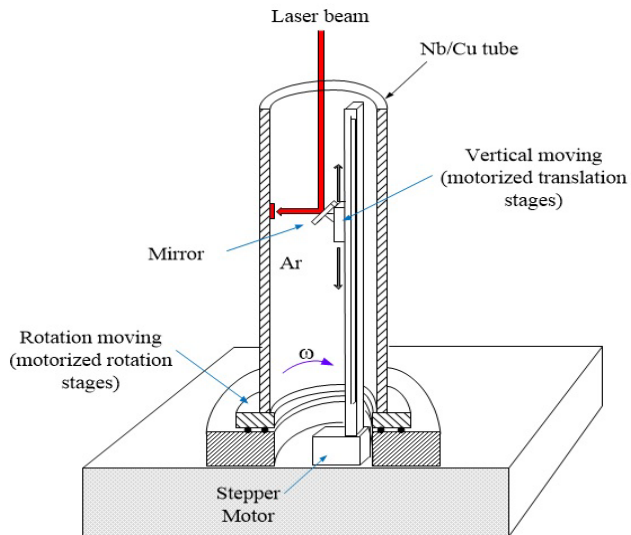
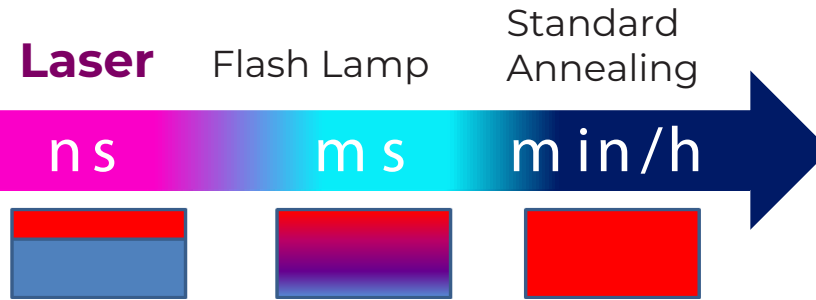


# Post Processing

# Laser Annealing

## Idea:

Anneal the coating without affecting the copper substrate to avoid diffusion at the interface



## Scaled to cylindrical geometry

Crystal size  $\uparrow \sim 20\%$   
Adhesion Nb/Cu  $\uparrow \sim 36\%$   
Roughness divided by  $\sim 2$

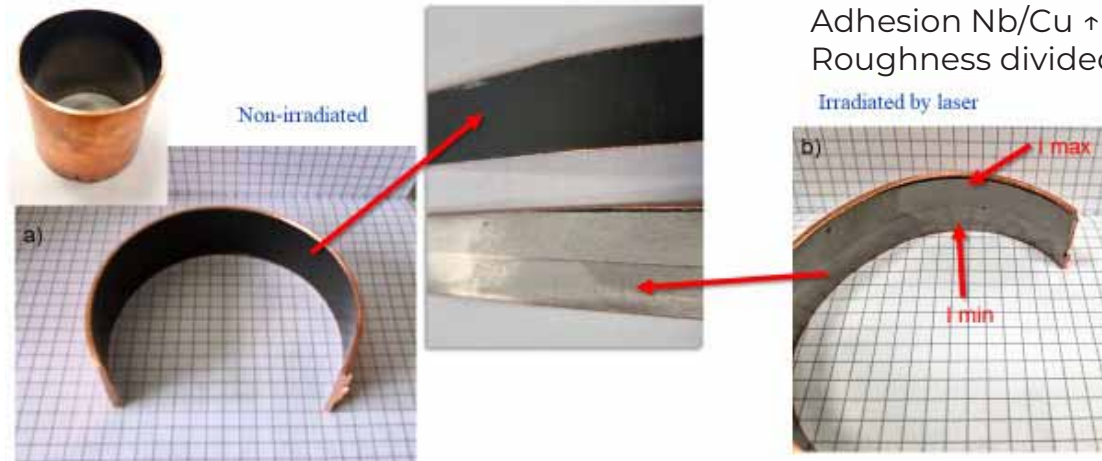
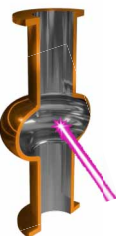


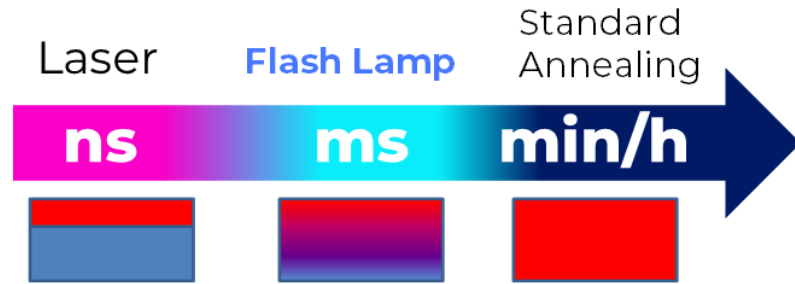
Fig. Samples formed from cylindrical copper tube with Nb film: (a) non-irradiated; (b) irradiated in Ar chamber by ns laser radiation.



Post Processing

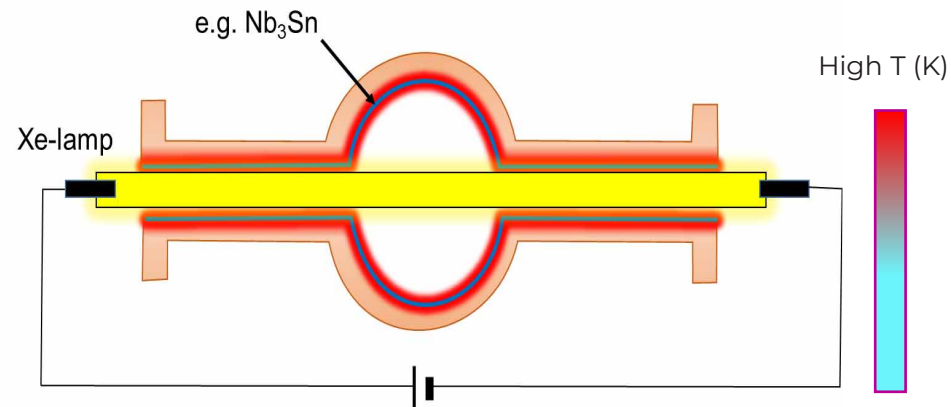
# ms-Flash Lamp Annealing

## ms-FLA

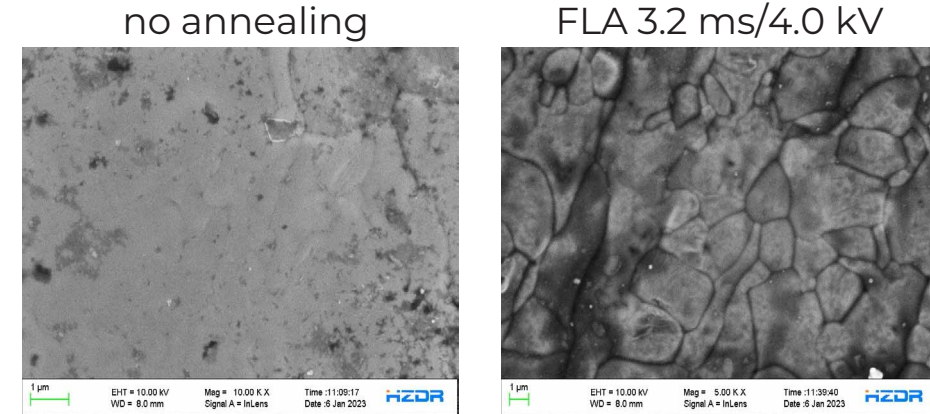


Only the coating layer is heated (even to 1000 °C) while the rest of the cavity remains cold

Improve coating crystallinity but too short to induce the diffusion of Cu

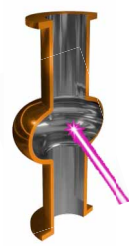
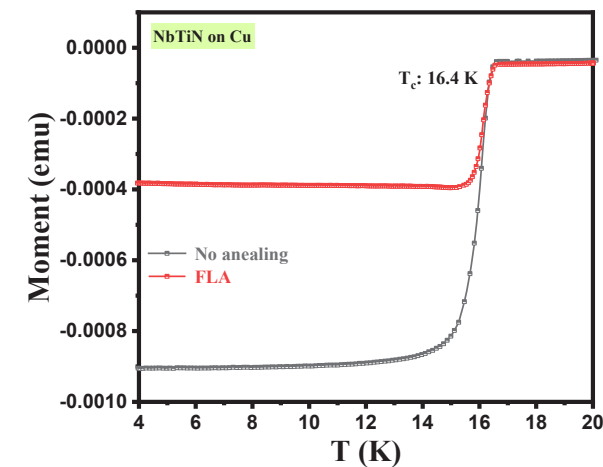


### First tests on NbTiN (Nb<sub>3</sub>Sn ongoing)



Crystalline grain size increased

T<sub>c</sub> remain stable



Post Processing

Courtesy of S. Prucnal and S. Zhou

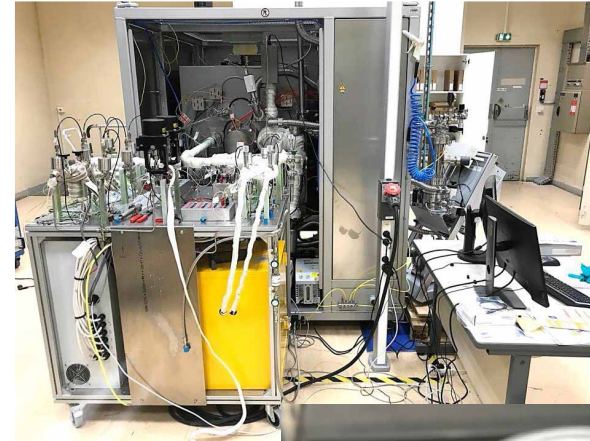
# Atomic Layer Deposition (ALD)



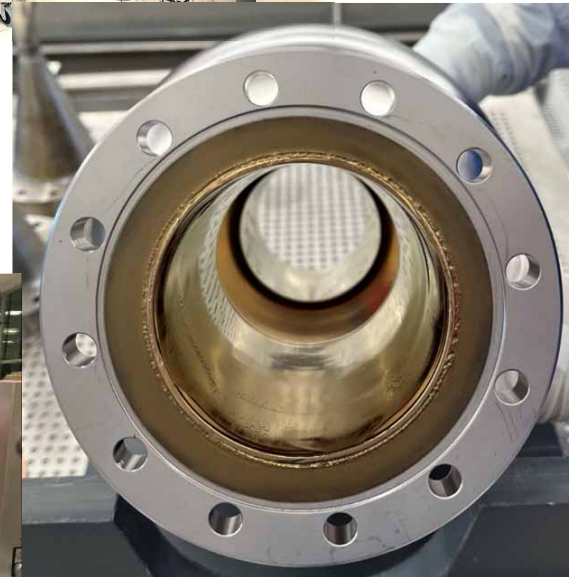
## Goal

### Deposition of functionalized layers :

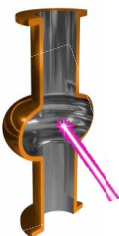
- ▶ Low secondary yield cap layer ( $\downarrow$  multipacting)
- ▶ SIS multilayers
- ▶ Dielectric surface engineering and doping



New ALD system @CEA  
Already coated several 1,3 Ghz cavities  
Compatible w. 700 MHz cavities



AIN-NbTiN coated cavity



Post Processing

Courtesy of Y. Kalboussi, C. Antoine and T. Proslie



# Atomic Layer Deposition (ALD)



**Yasmine Kalboussi**

**Talk today at 10:00: WEIBA01**

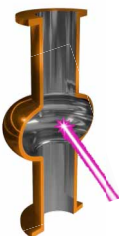
Surface Engineering by ALD for Superconducting RF Cavities

- ▶ Low secondary yield cap layer (↓ multipacting)
- ▶ SIS multilayers
- ▶ Dielectric surface engineering and doping

New ALD system @CEA  
Already coated several 1,3 Ghz cavities  
Compatible w. 700 MHz cavities



AIN-NbTiN coated cavity



Post Processing

Courtesy of Y. Kalboussi, C. Antoine and T. Proslir



# SC Properties Evaluation

# DC/AC Superconducting Properties Evaluation



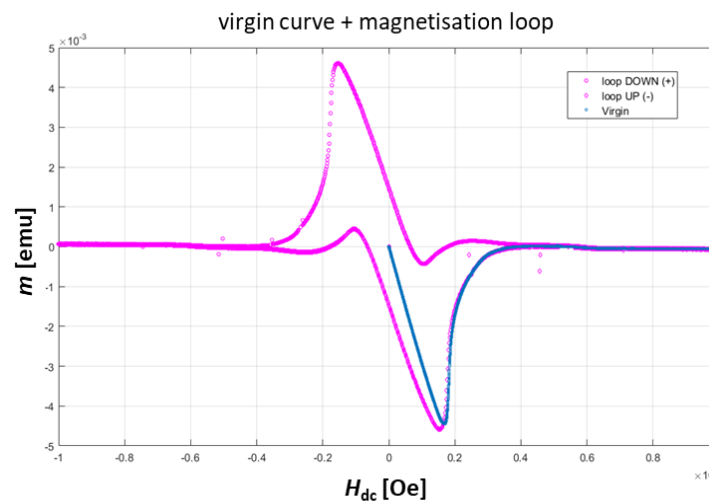
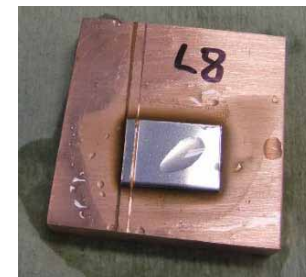
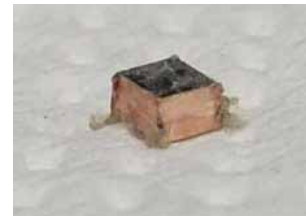
INSTITUTE OF  
ELECTRICAL ENGINEERING SAS



## DC magnetisation measurements

Vibrating Sample Magnetometer

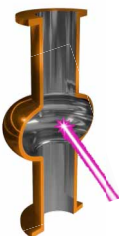
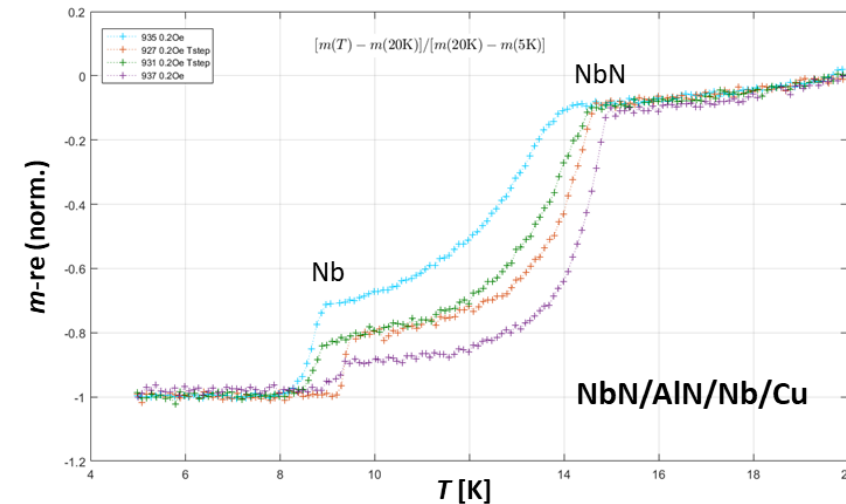
Small planar samples (~ 2x2 mm – cutting)



## AC magnetisation measurements

Susceptibility – temperature scans

Determining  $T_c$ 's of different films in Multilayer and SIS samples



Post Processing

Courtesy of E. Seiler

# Magnetic Field Penetration

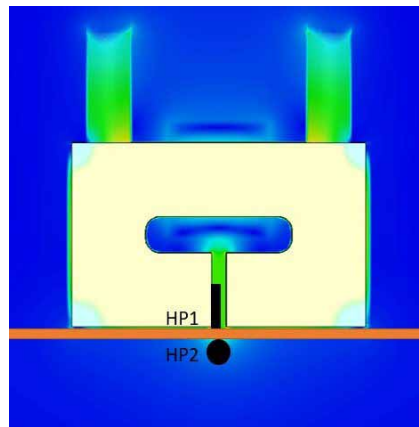
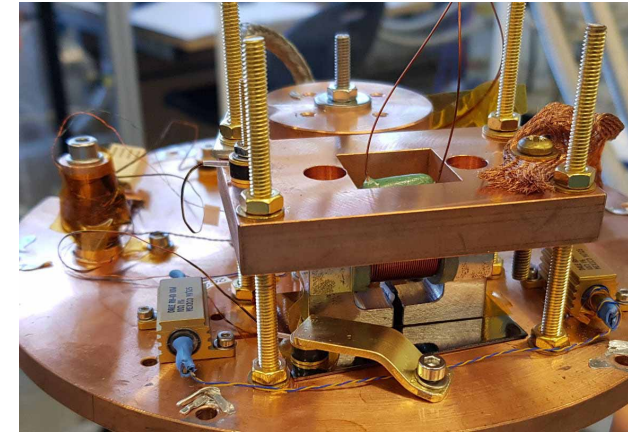


Science and  
Technology  
Facilities Council

Thin Film samples can be compared in conditions similar to ones in the cavity

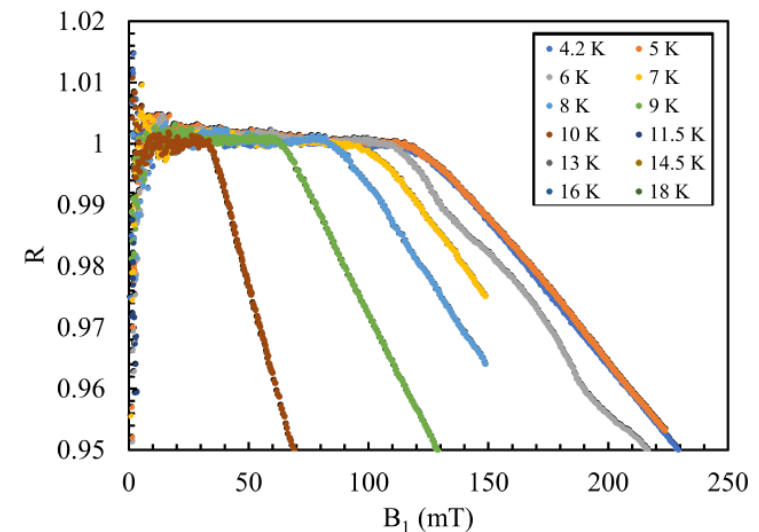
- ▶ DC magnetic field parallel to the surface
- ▶ Magnetic field applied from one side of the sample (similar to an SRF cavity)

Applied and penetrated field measured by Hall probe sensors



$$R = 1 - \frac{B_2}{B_1}$$

i.e. SC is in Meissner state when  $R = 1$



SC properties  
evaluation

Courtesy of L. Smith



# Magnetic Field Penetration



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Thin Film samples can be compared in conditions  
si

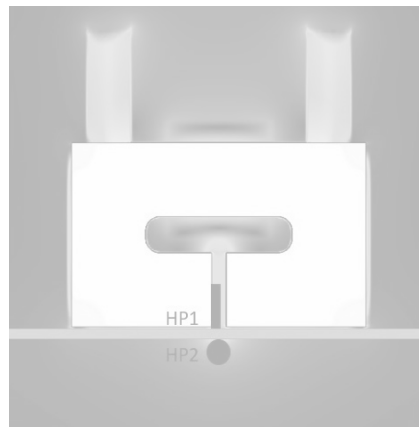


**Liam G. P. Smith**

**Poster on Monday: MOPMB012**

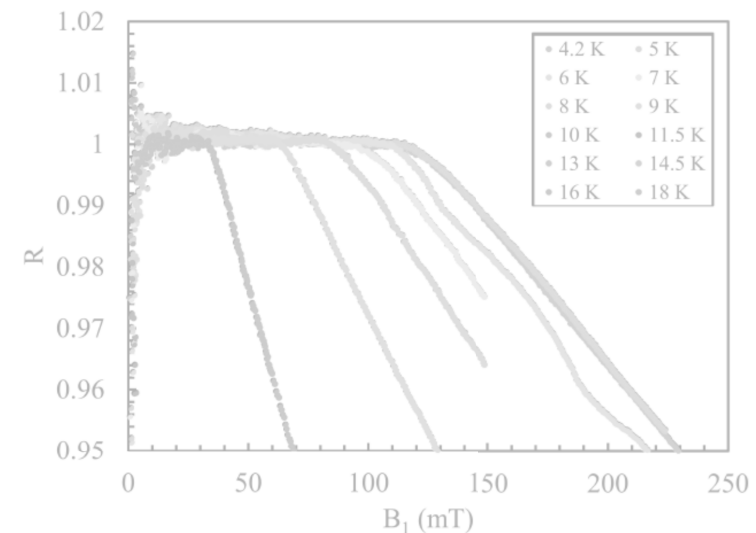
Investigation, Using Nb Foils to Characterise the Optimal Dimensions of Samples Measured by the Magnetic Field Penetration Facility

Applied and penetrated field  
measured by Hall probe sensors



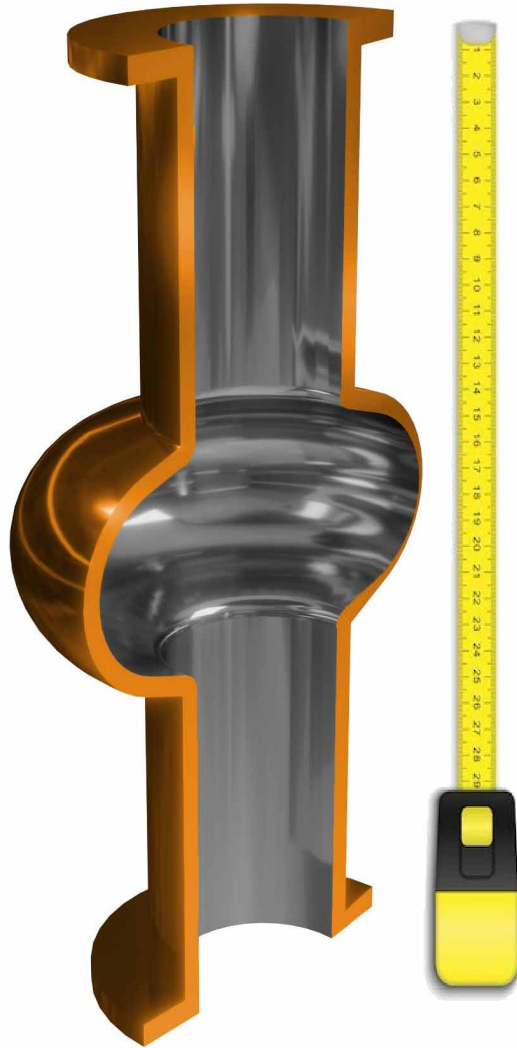
$$R = 1 - \frac{B_2}{B_1}$$

i.e. SC is in Meissner state when  $R = 1$



SC properties  
evaluation

Courtesy of L. Smith



# RF Measurements

# Sample RF test with 7.8 GHz Choke cavity



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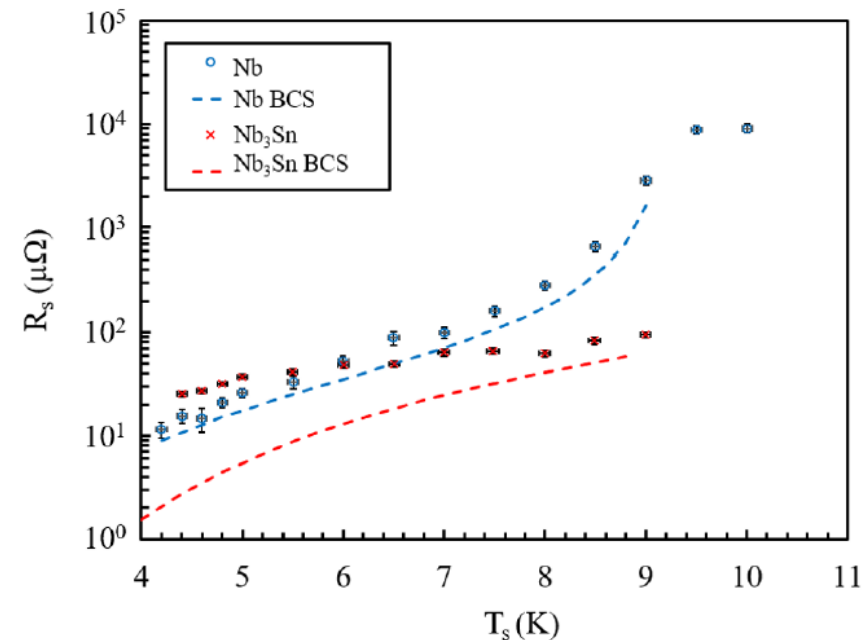
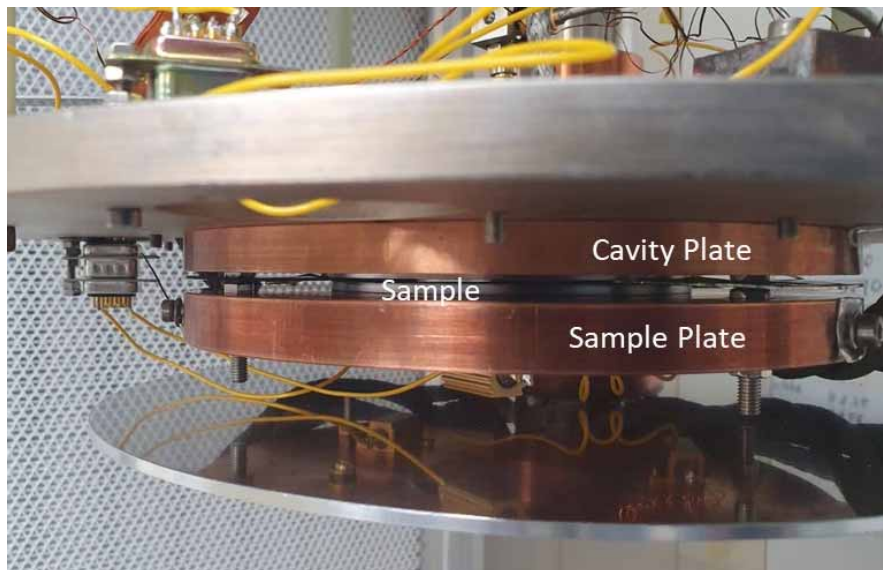


Operation with a closed-cycle refrigerator:  $T_{cavity} = 4.0$  K and  $T_{sample} = 4.0$  K

Low power ( $\leq 1.0$  W) measurements with an emphasis on fast turn-around time ( $\sim 2$  days sample)

**Flat Sample** – a disk diam. 90 - 130 mm

*An example of  $R_s(T_s)$  measurements for Nb and Nb<sub>3</sub>Sn TF planar samples with the choked cavity*



RF measurements

Courtesy of D. Seal

# 6 GHz split cavity



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Technology  
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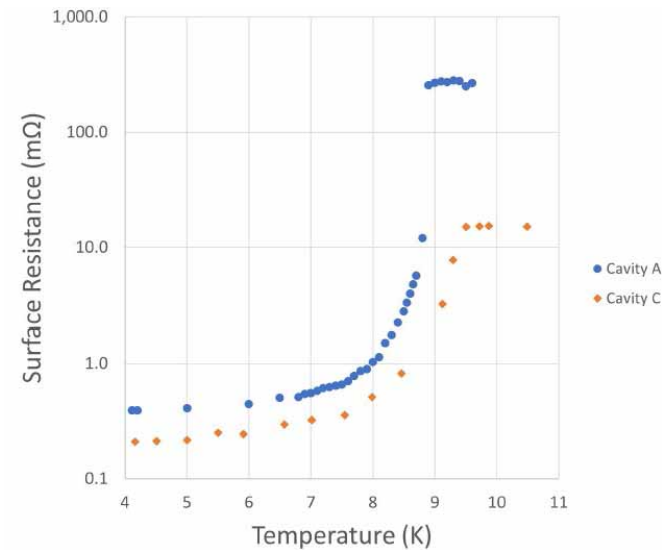
- ▶ An idea suggested by G. Burt (CI)
- ▶ The cavity cut is along the electric field lines, i.e. electric current is not crossing the cut
- ▶ Easy to coat with either conventional planar magnetron or in tubular geometry used for RF cavities
- ▶ Easy to inspect
- ▶ Two 6 GHz cavities were Nb coated and tested at  $4.2 \text{ K} \leq T \leq 11 \text{ K}$



*Nb thin films coated split cavity*



*Split cavity mounted on the cold head  
for cryogenic measurements*



*Surface resistance  $R_s$  as a function of temperature  
for Nb thin films coated split cavity*



RF measurements

Courtesy of N. Leicester, T. Sian, and J. Conlon



# 6 GHz split cavity



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- An idea suggested by G. Burt (CI)
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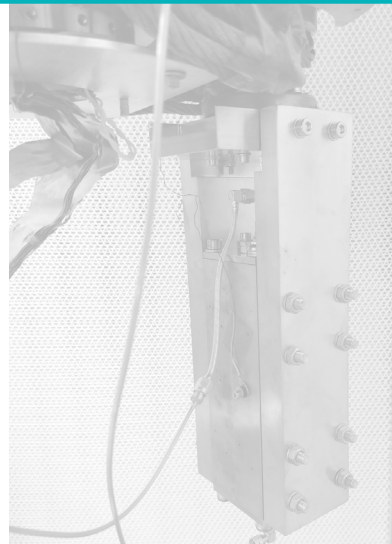
**Nathan Leicester**

**Poster on Monday: MOPMB001**

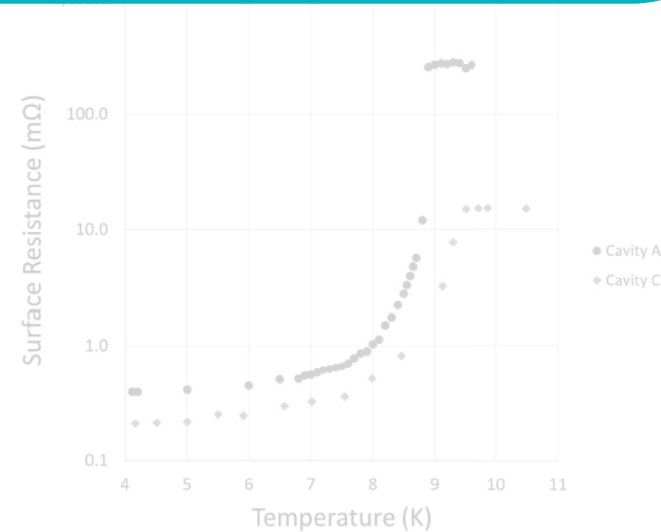
Development and Testing of Split 6 GHz cavities with Niobium Coatings



*Nb thin films coated split cavity*



*Split cavity mounted on the cold head for cryogenic measurements*



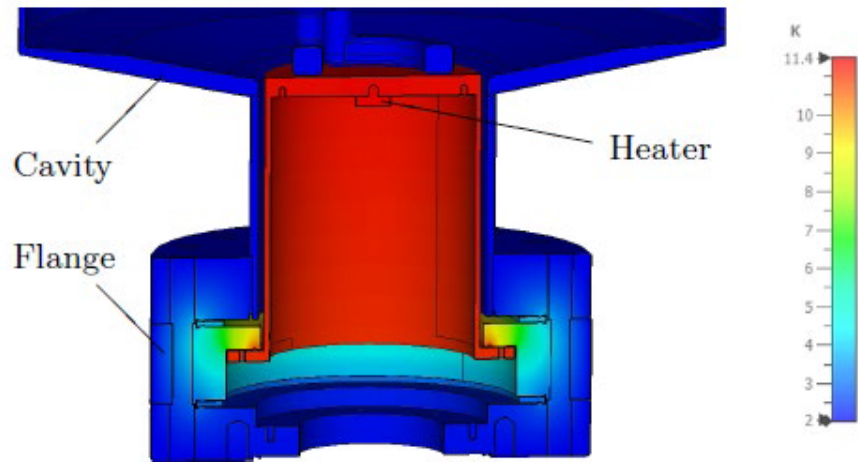
*Surface resistance  $R_s$  as a function of temperature for Nb thin films coated split cavity*



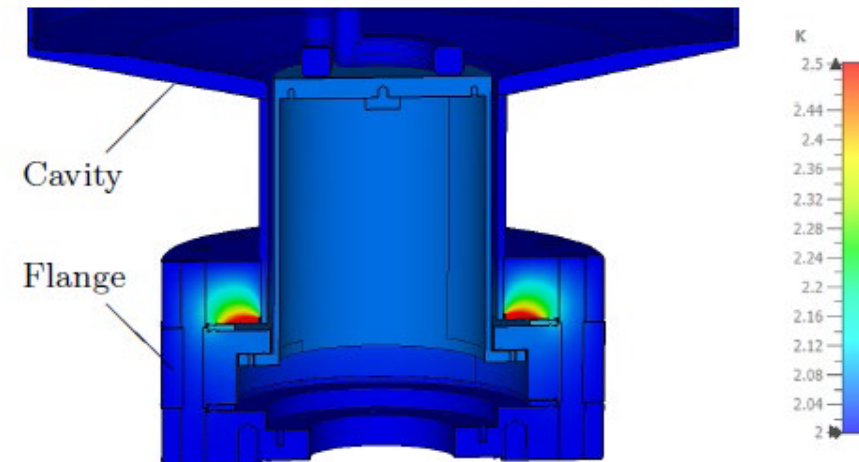
RF measurements

Courtesy of N. Leicester, T. Sian, and J. Conlon

# QuadruPole Resonator



RF losses on nc adapter flange lead to **unwanted heating of the sample** compromising the measured  $R_{res}$  value – resulting in a **systematic error of 12 nOhm**



**A SC coating of the adapter flange eliminates the RF heating of the sample**

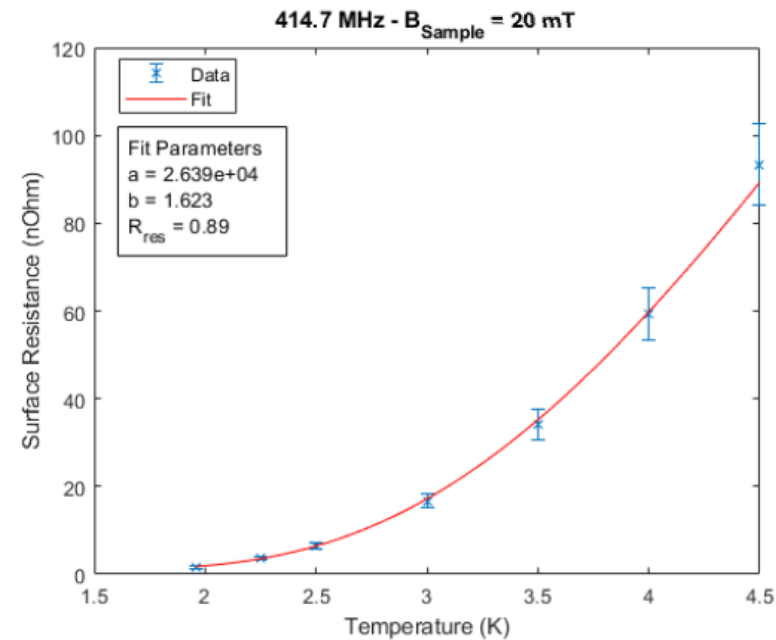
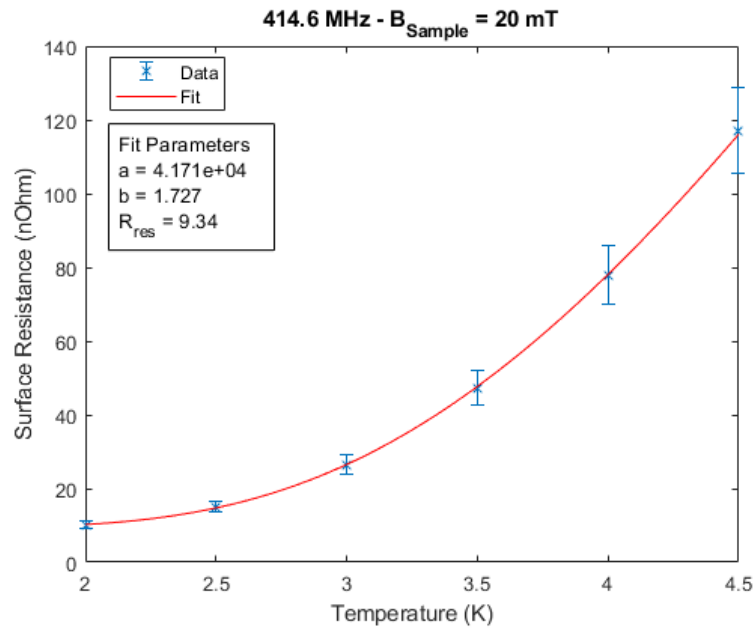
*Keckert, S., et al. (2021). "Mitigation of parasitic losses in the quadrupole resonator enabling direct measurements of low residual resistances of SRF samples." AIP Advances **11(125326)**.*



RF measurements

Courtesy of O. Kugert and S. Keckert

# QuadruPole Resonator



State-of-the-art chemically polished Nb sample

Same sample after optimized metallographic polishing  
 $R_{\text{res}} < 1 \text{ nOhm}$  directly measured with QPR

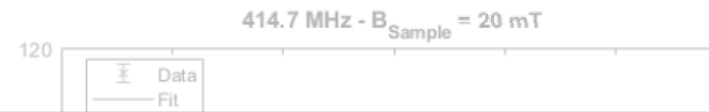
- ▶ Metallographic polishing produce high quality baseline samples for thin-film investigations
- ▶ QPR is now able to measure  $R_{\text{res}}$  with same accuracy and precision as an SRF cavity



RF measurements

Courtesy of O. Kugert and S. Keckert

# QuadruPole Resonator



**Oleksandr Hryhorenko**

**Talk today at 12:20: WEIXA06**

Recent advances on metallographic polishing for SRF application



**Oleksandr Hryhorenko**

**Poster today: WEPWB050**

Exploring innovative pathway of cavity fabrication for SRF application

State-of-the-art chemically polished Nb sample

Same sample after optimized metallographic polishing  
 $R_{res} < 1n\Omega$  directly measured with QPR

Metallographic polishing produce high quality baseline samples for thin-film investigations

QPR is now able to measure  $R_{res}$  with same accuracy and precision as an SRF cavity



RF measurements

Courtesy of O. Kugert and S. Keckert



# 1.3 GHz cavity testing



Cold-test inserts @ INFN LASA

- ▶ Facilities ready at  
CEA, HZB, INFN LASA  
INFN LNL for 6 GHz cavities

- ▶ Assembling in process at STFC



New 1.3 GHz insert @ STFC



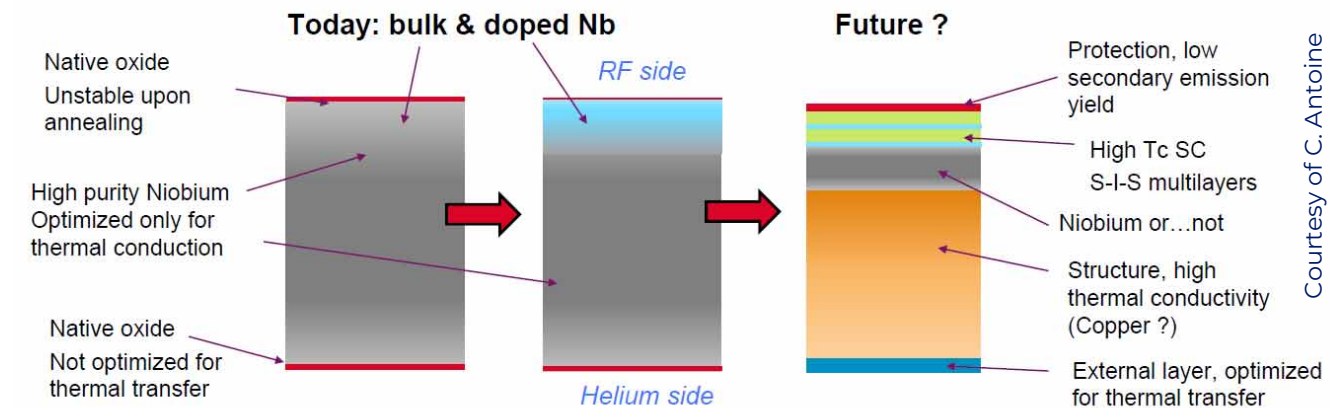
RF measurements

Courtesy of O. Malyshev

# Conclusion

- ▶ **Great advancements** on planar samples
- ▶ First **RF results** on QPR expected by the **end of the year**
- ▶ The **project is on the track** to produce the first 1.3 GHz prototype in 2025

Thin film SRF presents multiple challenges that can be **won collaborating** among the different Laboratories



Courtesy of C. Antoine

Our Vision of the future for SRF





cristian.pira@lnl.infn.it

# Thank You for Your Attention!



PROGRESS IN EUROPEAN THIN FILM ACTIVITIES